

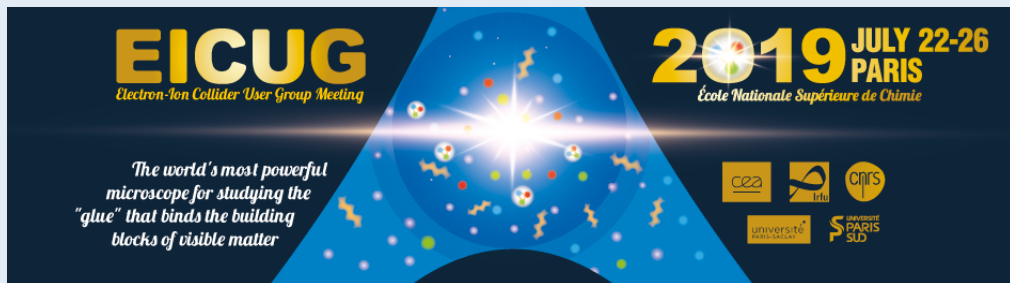


The ALICE Inner Tracking System Upgrade and future plans

Vito Manzari (INFN Bari, vito.manzari@cern.ch)

Eol document, Dec 2018, submitted to European Strategy for Particle Physics Preparatory Group (arXiv: 1902.01211)

ALICE-PUBLIC-2018-013 <https://cds.cern.ch/record/2644611>



- **ALICE LS2 Upgrade**
- **LS2 Inner Tracking System Upgrade (ITS2)**
 - Motivations
 - Detector layout
 - ALPIDE: Monolithic Active Pixel Sensor
 - Main components and material budget
- **Concepts for a future fast and lightweight heavy-ion detector**
 - Motivations
 - Design guidelines
 - Vertex detector
 - New MAPS sensor
 - Roadmap

New Inner Tracking System (ITS)

Novel MAPS technology

- CMOS Active Pixel Sensors
- improved resolution, less material, faster readout

New Muon Forward Tracker (MFT)

- CMOS Active Pixel Sensors
- vertex tracker at forward rapidity

New TPC Readout Planes

Largest GEM application

- 4-GEM detectors, new electronics
- continuous readout

New trigger detectors (FIT, AD)

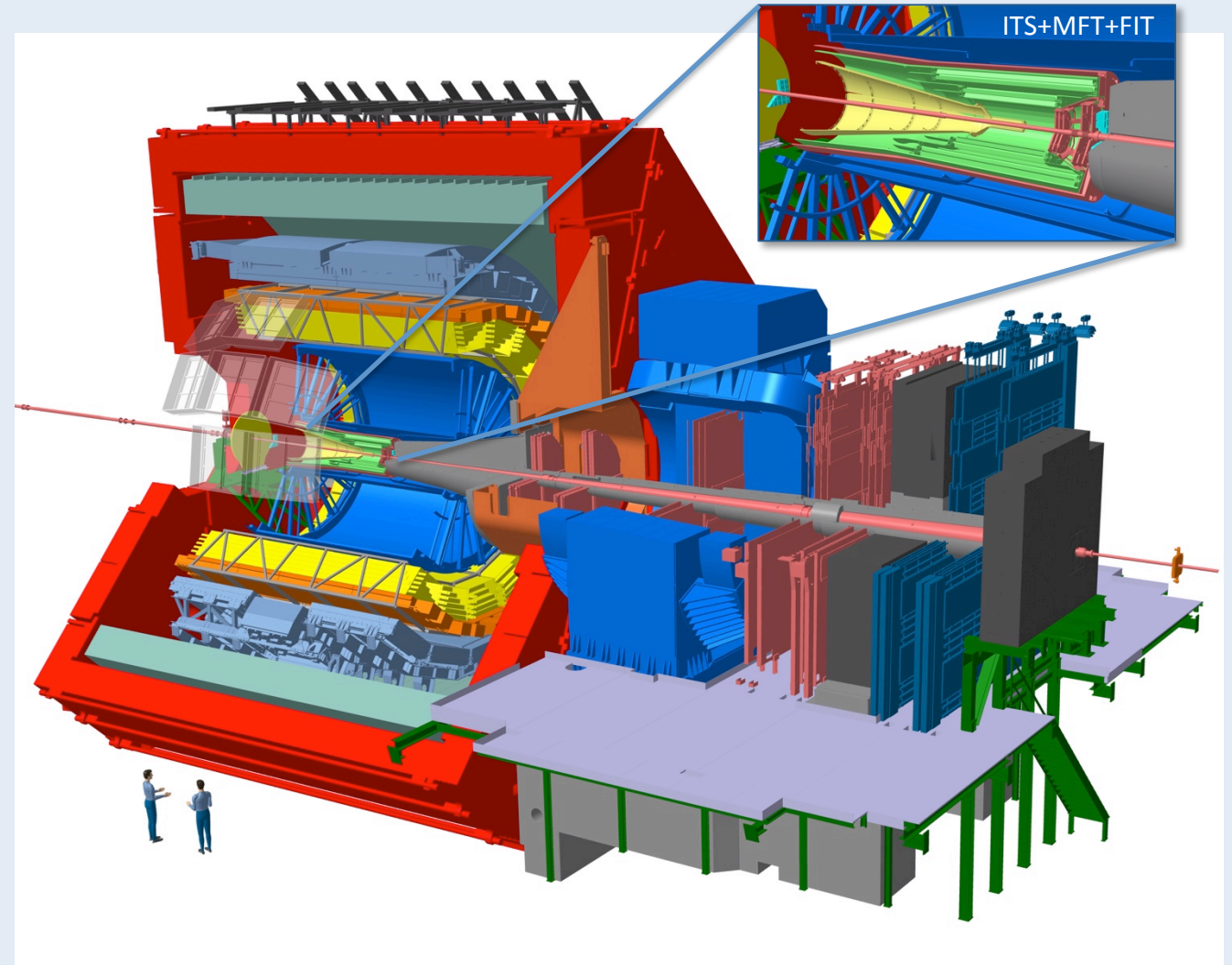
- Centrality, event plane

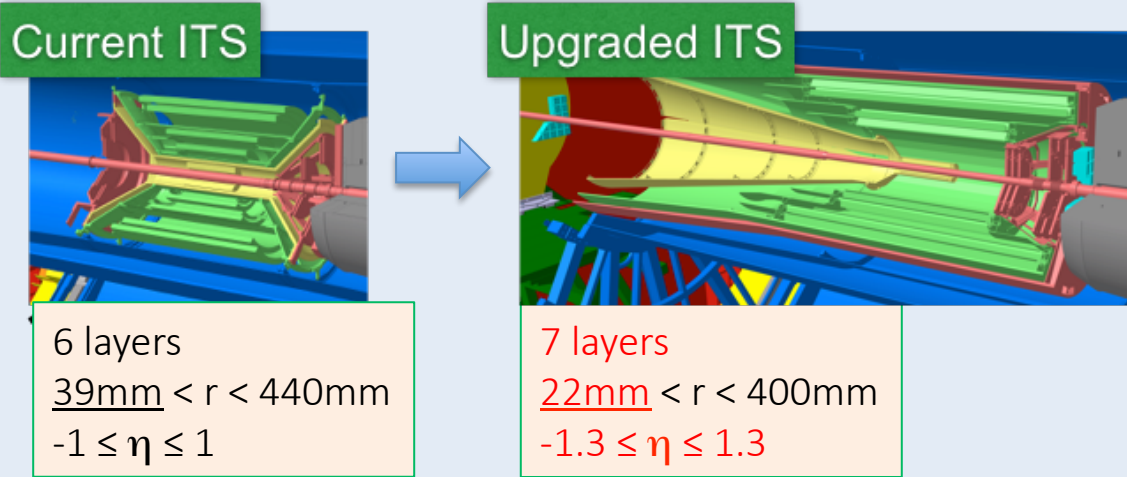
Upgrades readout

- TOF, TRD, MUON, ZDC, Calorimeter

Integrated Online-Offline system (O²)

- Record minimum-bias Pb-Pb data at > 50kHz (currently ~ 1 kHz)





Current ITS
 6 layers
 $39\text{mm} < r < 440\text{mm}$
 $-1 \leq \eta \leq 1$

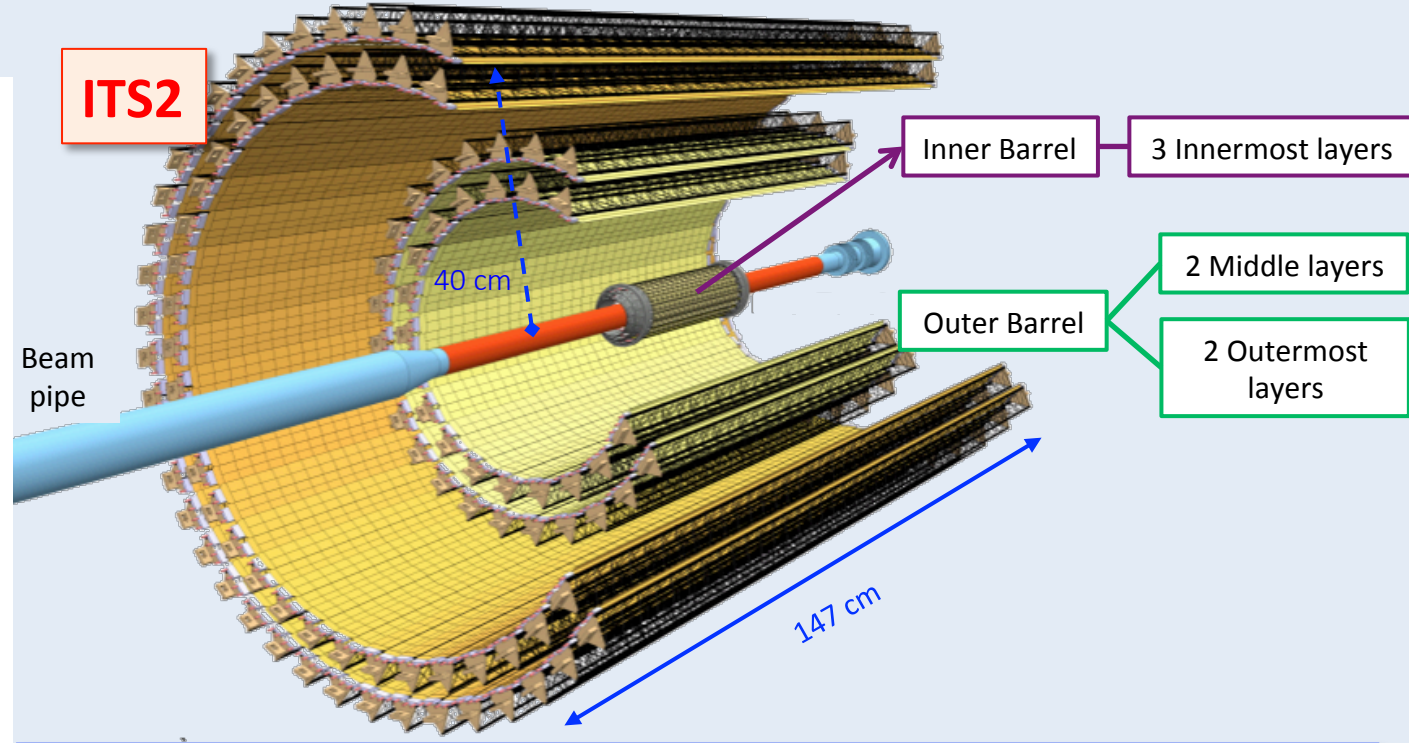
Upgraded ITS
 7 layers
 $22\text{mm} < r < 400\text{mm}$
 $-1.3 \leq \eta \leq 1.3$

Motivations and goals

- Improved vertex and tracking precision and efficiency at low p_T
 - ➡ closer to IP, smaller pixels, less material
- Faster readout

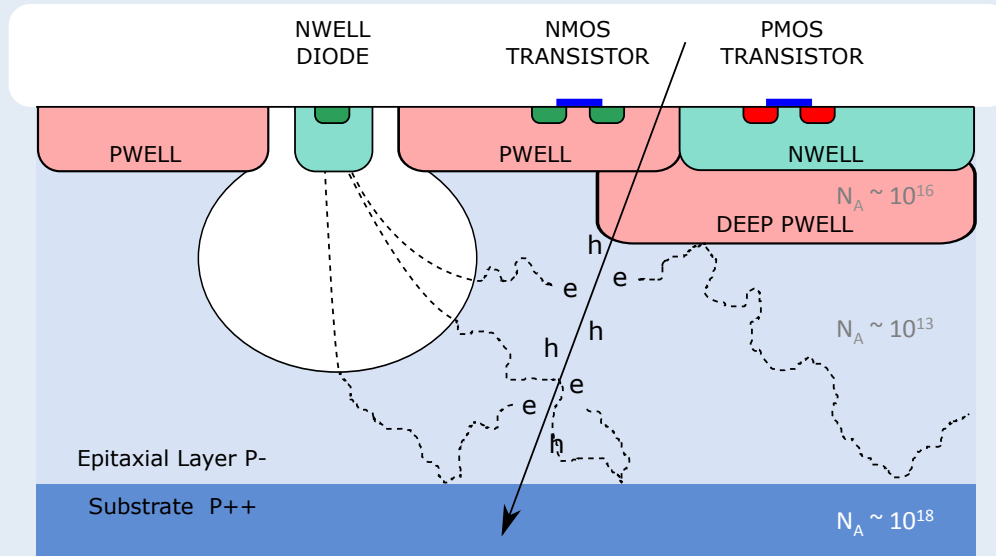
Based on novel MAPS ALPIDE (vs ITS1)

- 10 m² active silicon area, 12.5 G-pixels
- Closer to interaction: **22 mm** (39mm)
- Higher intrinsic resolution (smaller pixels):
 - ~5 μm in $r\phi$ and z directions (12 and 100 μm)
- Power density < 40mW / cm²
- Max particle rate ~ 100MHz /cm² (w/o pile-up)
- Fake hit rate: < 1Hz/cm²
- Less material: ~0.3% X_0 for Inner Barrel (1.1% X_0)
- Faster readout: **100 kHz Pb-Pb** (1 kHz)

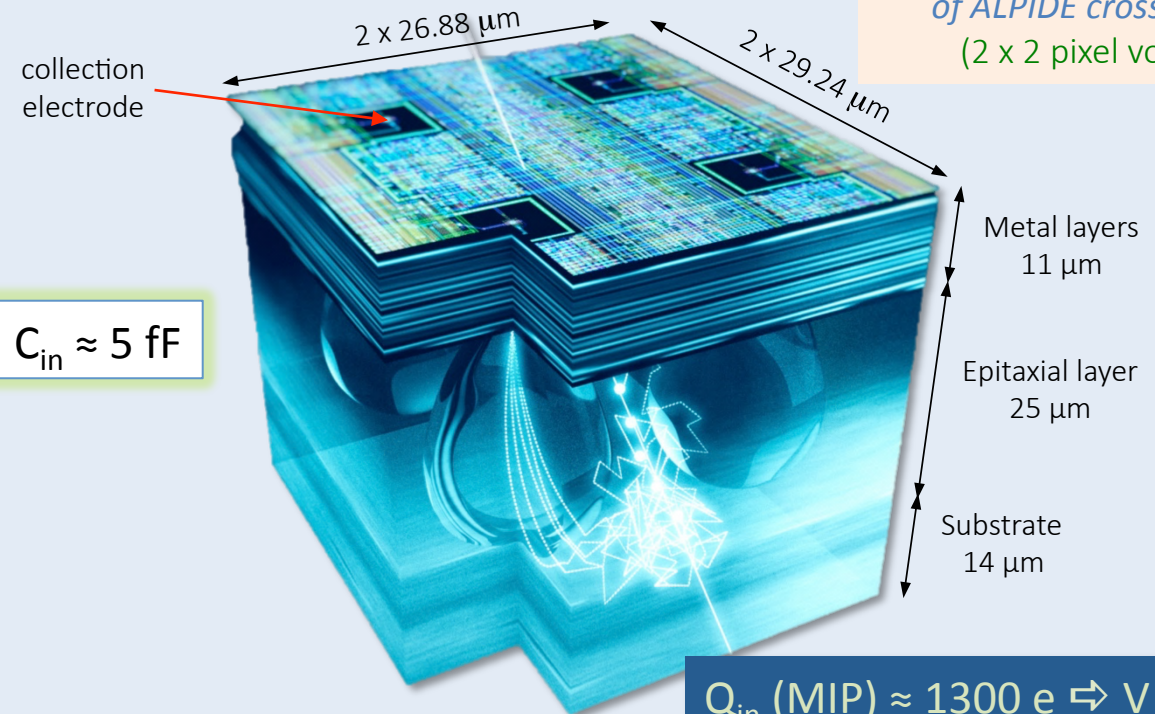


⇒ further improvements exploiting technological innovations

ALPIDE: CMOS Pixel Sensor using TJ 0.18 μm CMOS Imaging Process



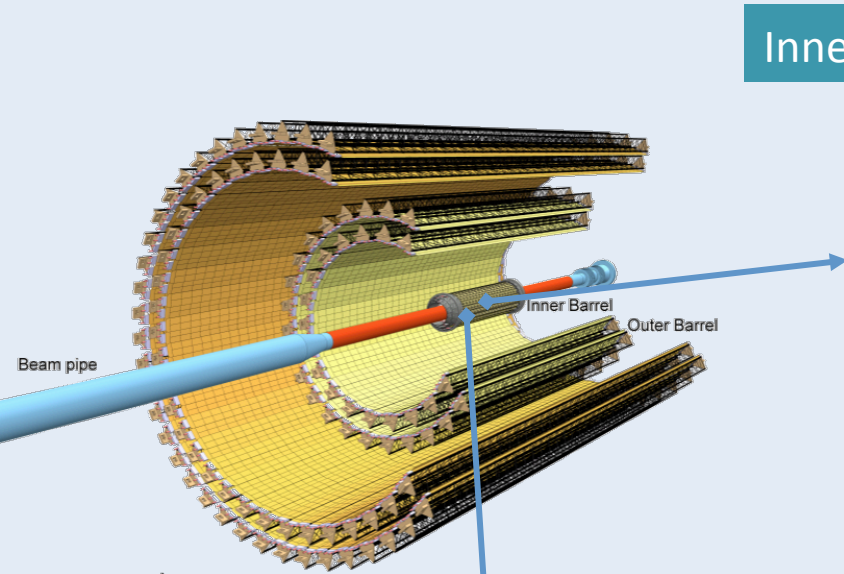
pixel capacitance $\approx 5 \text{ fF}$ (@ $V_{bb} = -3 \text{ V}$)



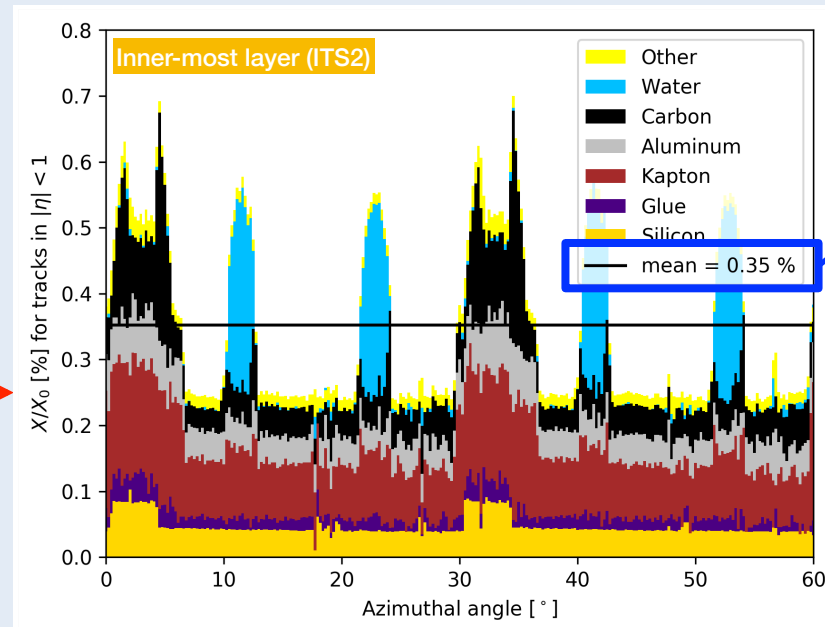
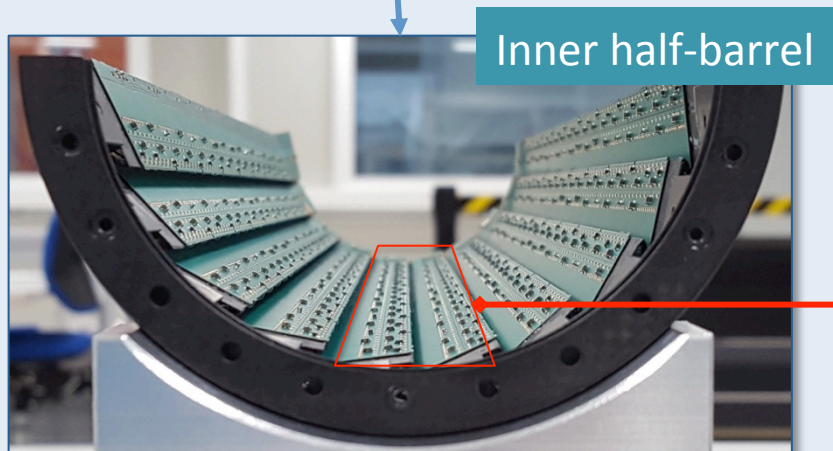
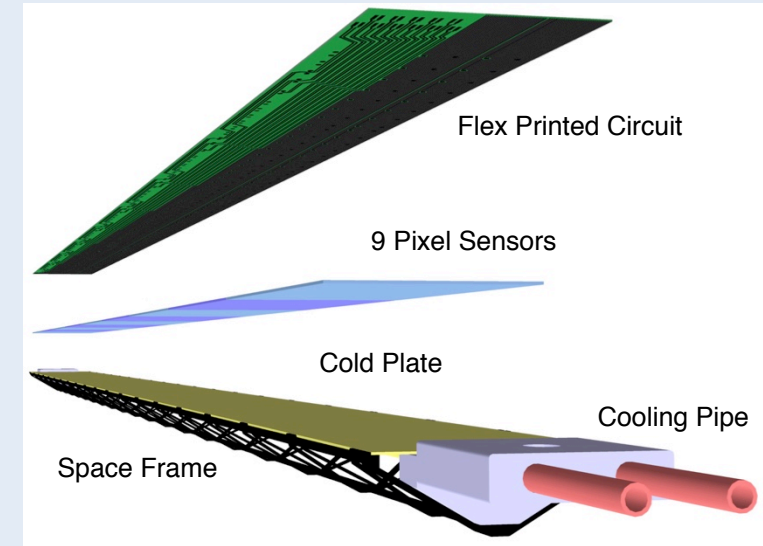
Artistic view of a SEM picture of ALPIDE cross section (2 x 2 pixel volume)

- ▶ High-resistivity ($> 1 \text{ k}\Omega \text{ cm}$) p-type epitaxial layer ($25 \mu\text{m}$) on p-type substrate
- ▶ Small n-well diode ($2 \mu\text{m}$ diameter), ~ 100 times smaller than pixel \Rightarrow low capacitance ($\sim \text{fF}$)
- ▶ Reverse bias voltage ($-6 \text{ V} < V_{BB} < 0 \text{ V}$) to substrate (contact from the top) to increase depletion zone around NWELL collection diode
- ▶ Deep PWELL shields NWELL of PMOS transistors

\rightarrow full CMOS circuitry within active area



Inner barrel

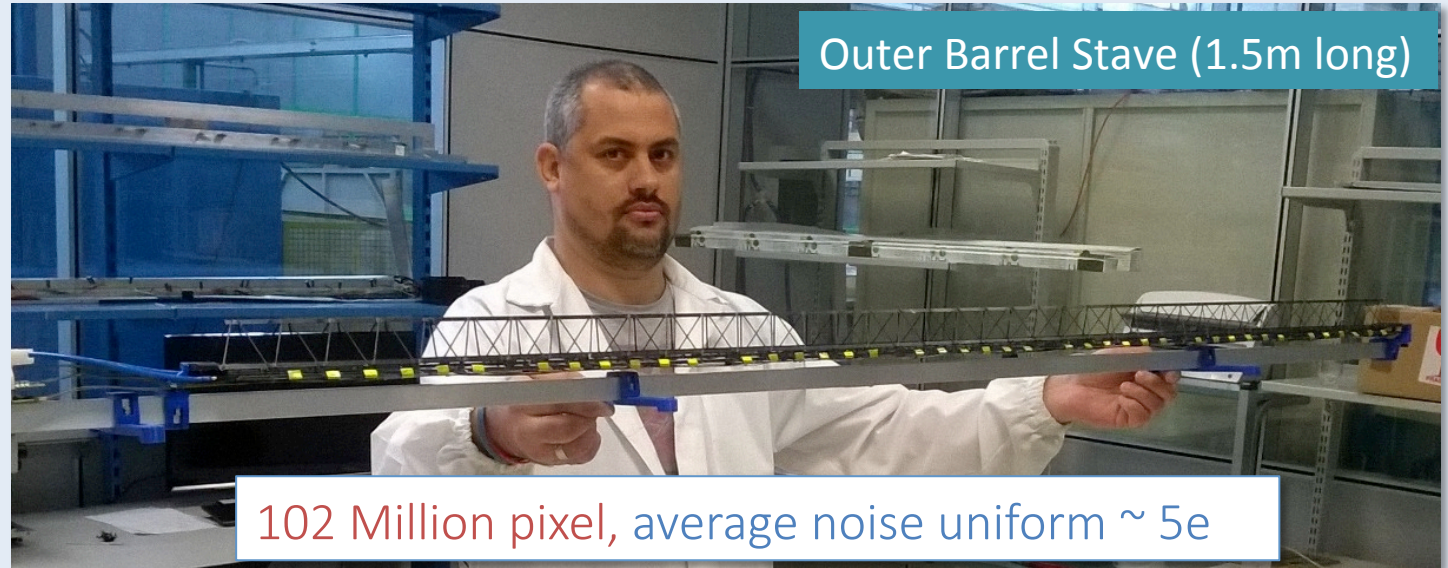


Silicon \Rightarrow only 15%

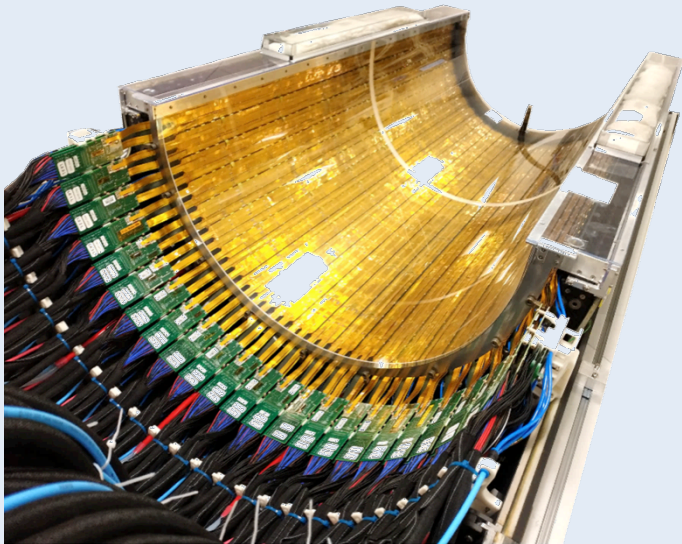
Layers - 0, 1 and 2



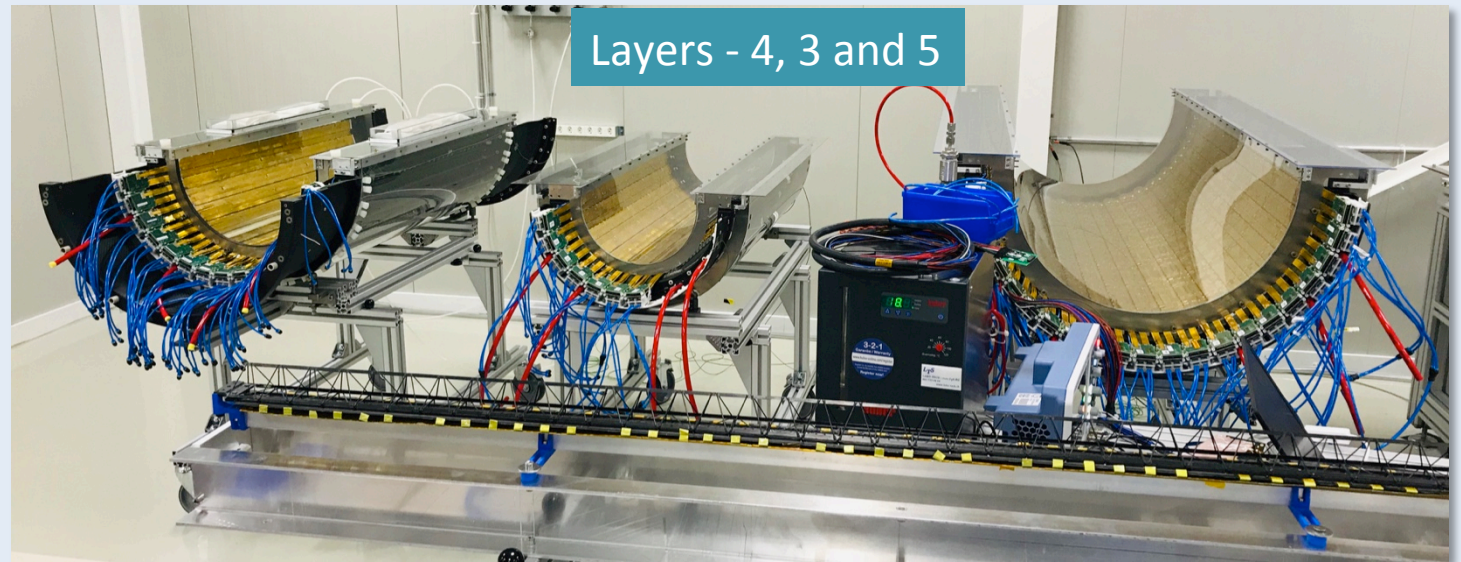
Outer Barrel Stave (1.5m long)



102 Million pixel, average noise uniform $\sim 5e$



Layers - 4, 3 and 5



TPC Continuous Readout with GEMs (Gas Electron Multiplier)

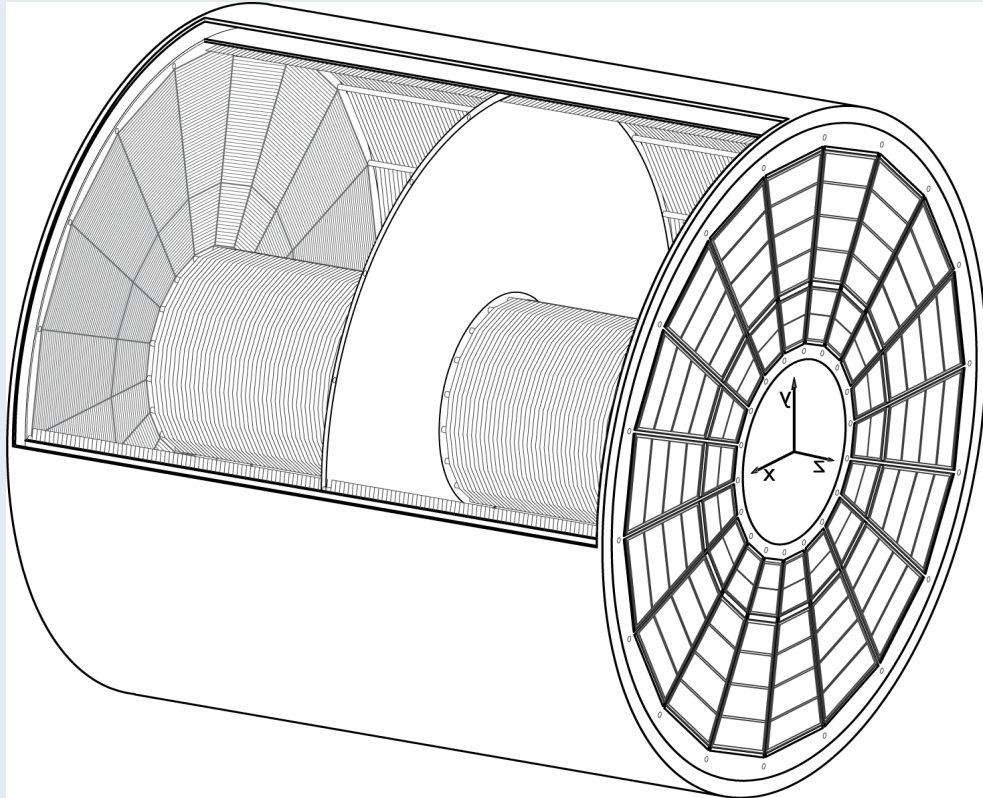
Gate-less TPC for continuous readout

Current MWPC: readout rate limited by ion backflow

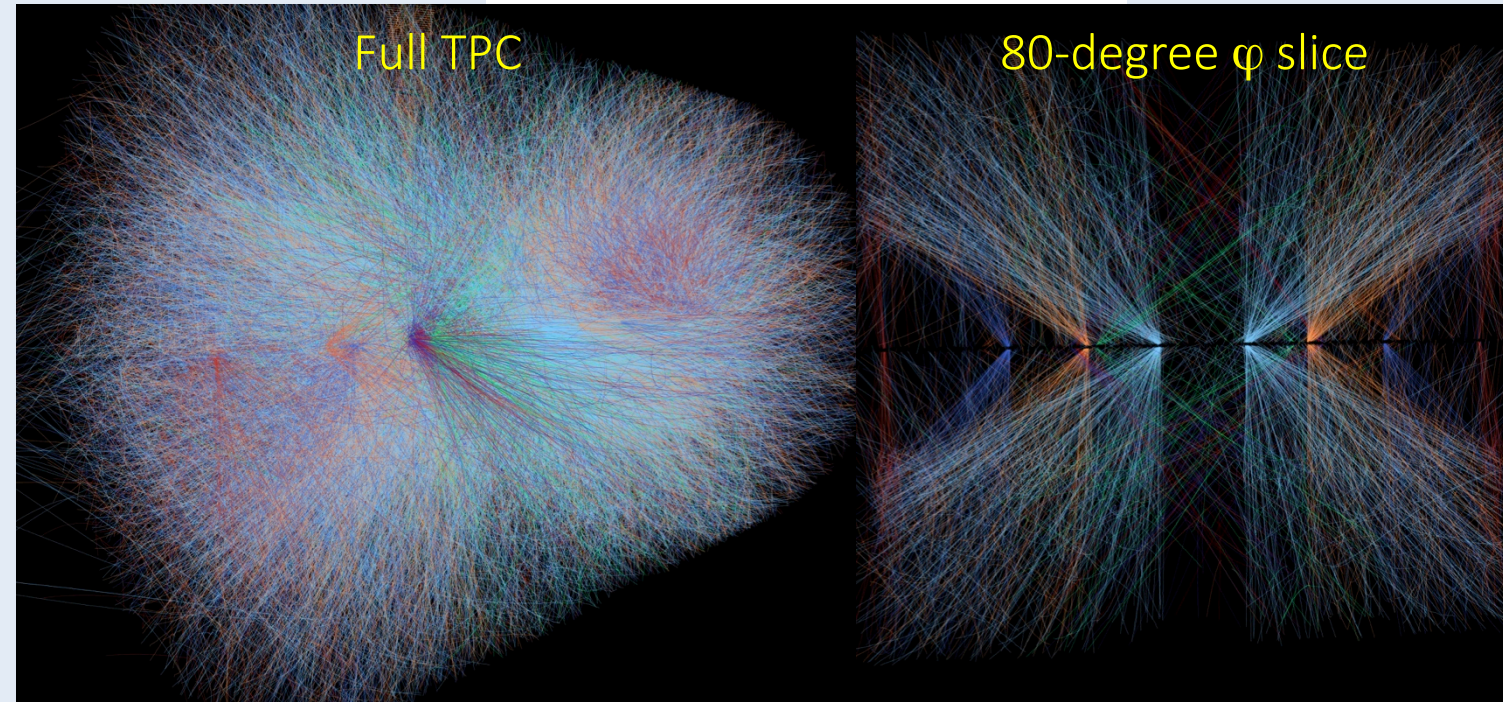
Operate TPC at 50 kHz \Rightarrow no gating grid

Need to minimize IBF \Rightarrow Replace MWPC with 4-GEMs

100 m² single-mask foils GEM production



Pb-Pb Collisions @ 50kHz



\Rightarrow GEM provides ion backflow suppression to $< 1\%$

\Rightarrow 524 000 pads readout continuously (10bit x 5MSPS) via 6552 links \Rightarrow 3.4 TByte/sec

With the LS2 upgrade, ALICE will reach the maximum rate with a spectrometer based on a TPC

⇒ Maximum interaction rate limited by space-charge (ions) accumulated in drift volume (**distortions $\approx 10\text{cm}$**) and track density (inner region **signal occupancy $\approx 40\%$**)

Running at higher rates seems excluded with a TPC

Running ALICE beyond RUN4? ⇒ Completely new detector without TPC

The use of CMOS technologies opens new opportunities

⇒ Vertex detectors, large area tracking detectors and digital calorimeters

- enhanced performance (very high **spatial** and **time** resolution)

an “all-MAPS” detector

☞ *Such a detector could play a central role in HI physics at the LHC in the 2030's*

Design guidelines

- Increase rate capabilities (factor 50 wrt to ALICE RUN4): $\langle L_{NN} \rangle \sim$ up to $10^{34} \text{ cm}^{-2}\text{s}^{-1}$
- Improve vertexing
 - Ultra-thin wafer-scale sensors with truly cylindrical shape, inside beampipe
 - spatial resolution $< 3\mu\text{m}$
 - material thickness $< 0.05\% X_0$ /layer
- Improve tracking precision and efficiency
 - About 10 layers with a radial coverage of 1m
 - Spatial resolution of about $5\mu\text{m}$ up to 1m
 - whole tracker could be less than $6\% X_0$ in thickness (at mid-rapidity)
- Tracking over a wide momentum range, down to a few tens of MeV/c, and rapidity coverage $|\eta| \leq 4$

Magnetic fields of $< 0.5\text{T}$ would be sufficient but 1T is also considered

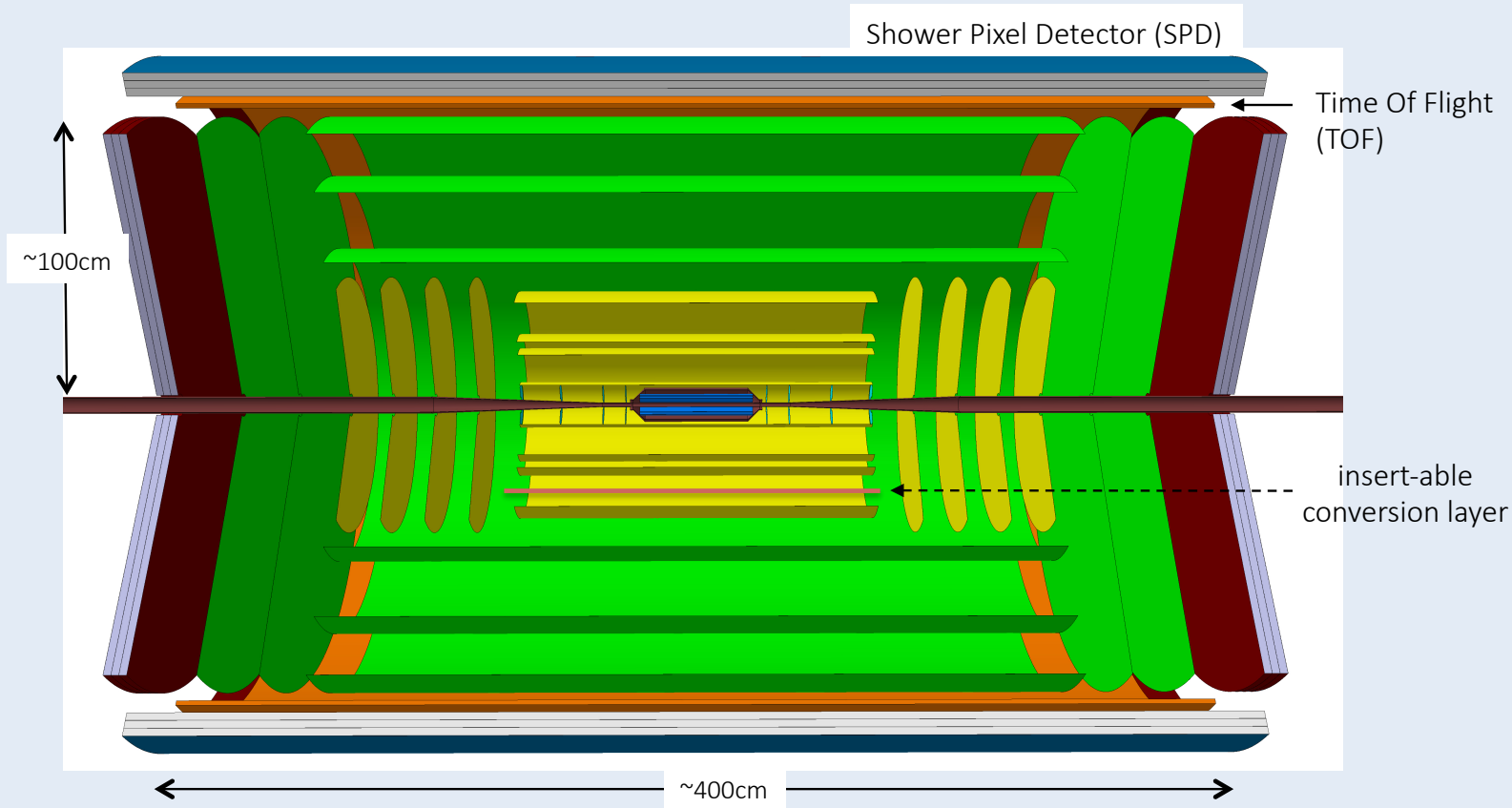
A new experiment based on a “all-silicon” detector

Tracker: ~10 tracking barrel layers (blue, yellow and green) based on CMOS sensors

Particle ID:

- TOF with outer silicon layers (orange)
- Shower Pixel Detector (outermost blue layer)

Extended rapidity coverage: **up to 8 rapidity units**



Magnetic Field

- $B = 0.5$ or 1 T

Spatial resolution

- Innermost 3 layers: $\sigma < 3\mu\text{m}$
- Outer layers: $\sigma \sim 5\mu\text{m}$

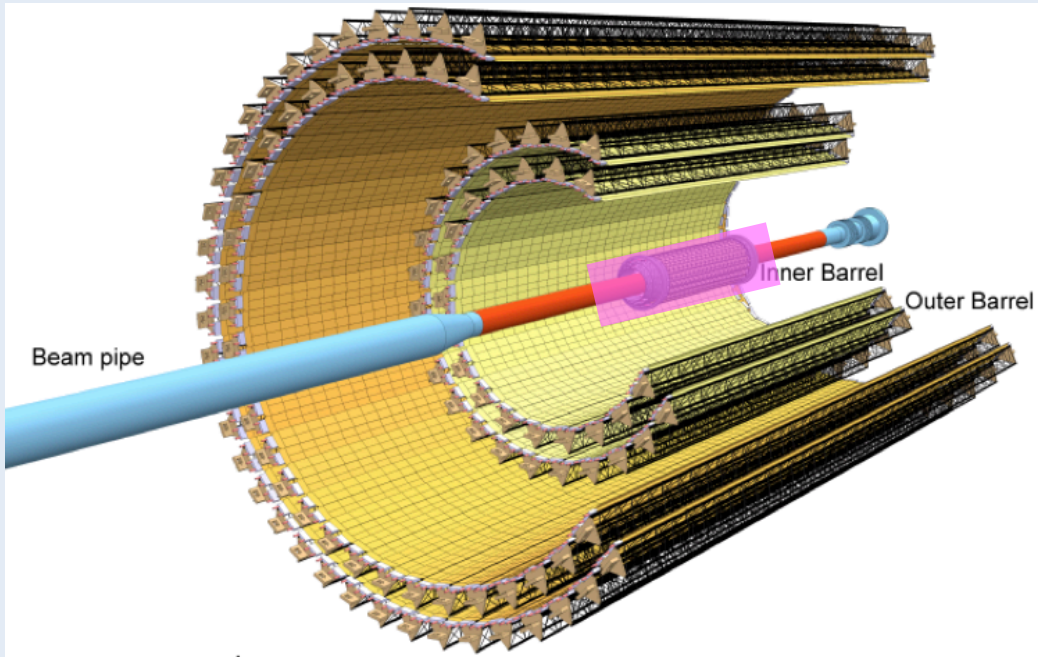
Vertex material thickness

- $X/X_0 \sim 0.05\%$ / layer

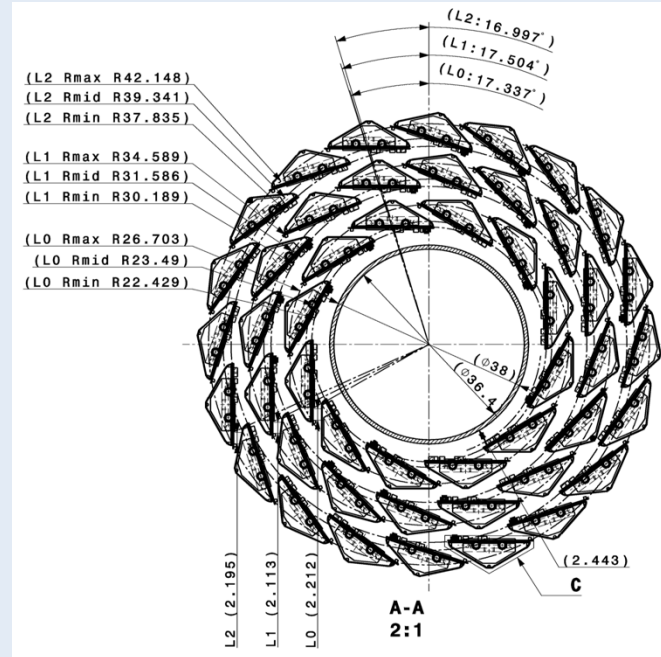
Time Measurement

Outermost layer integrates high precision time measurement ($\sigma_t \sim 20\text{ps}$)

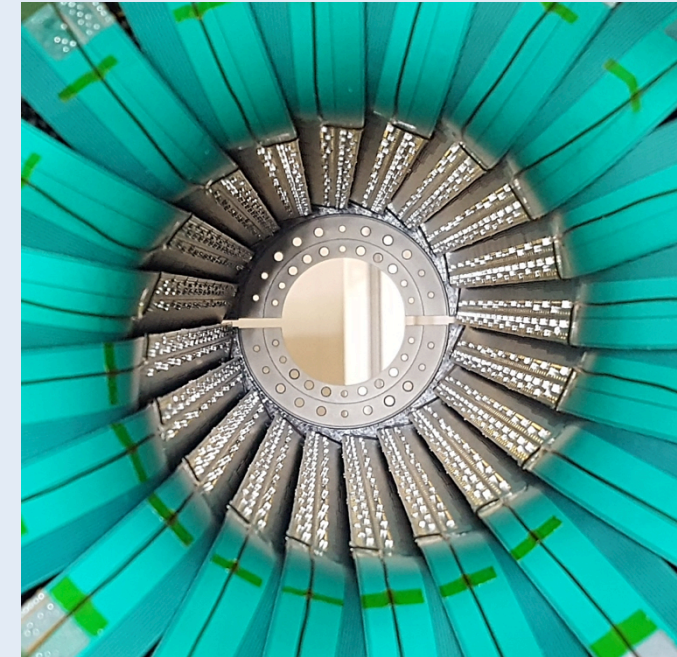
ITS2 layout



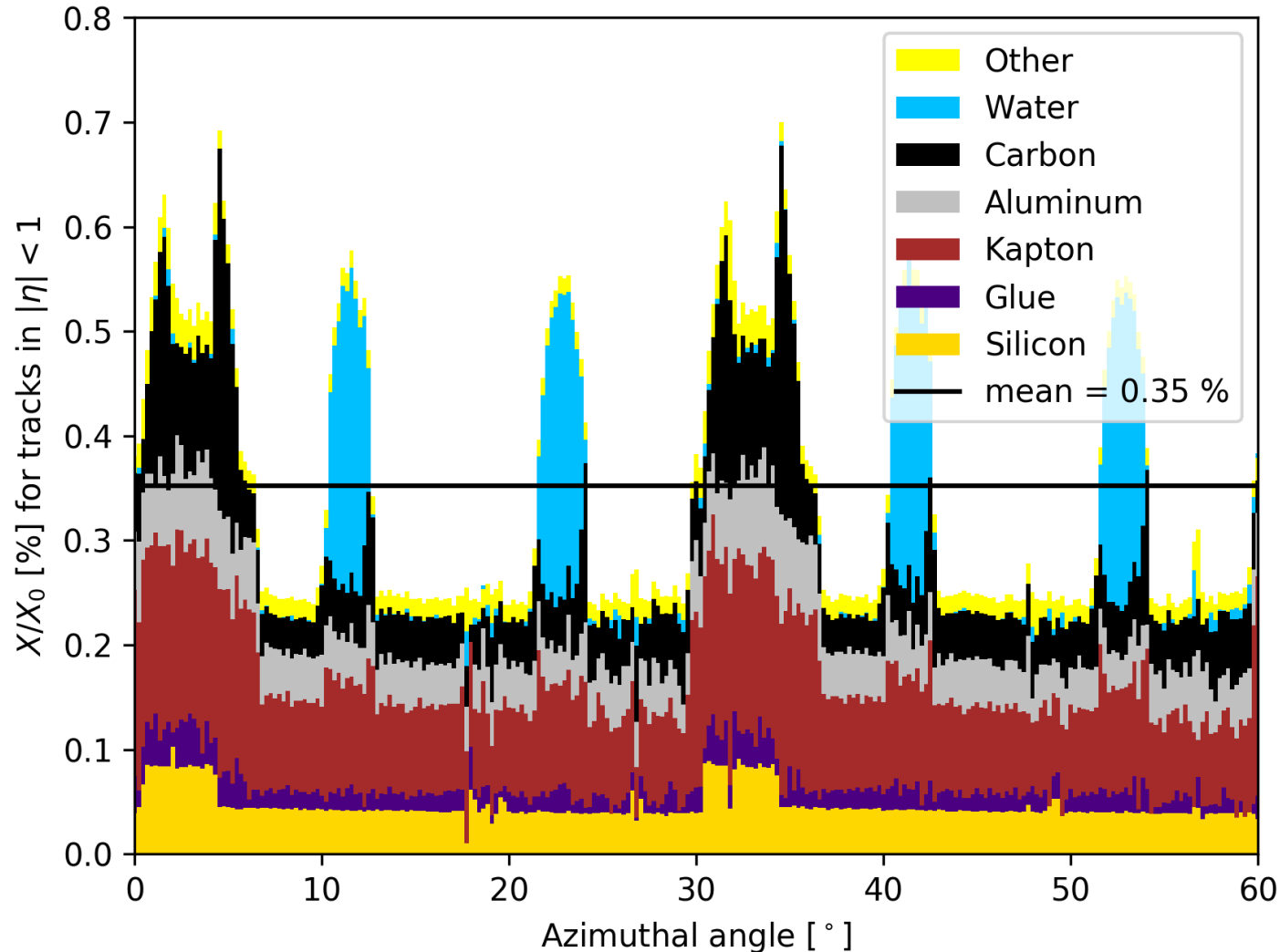
Inner barrel



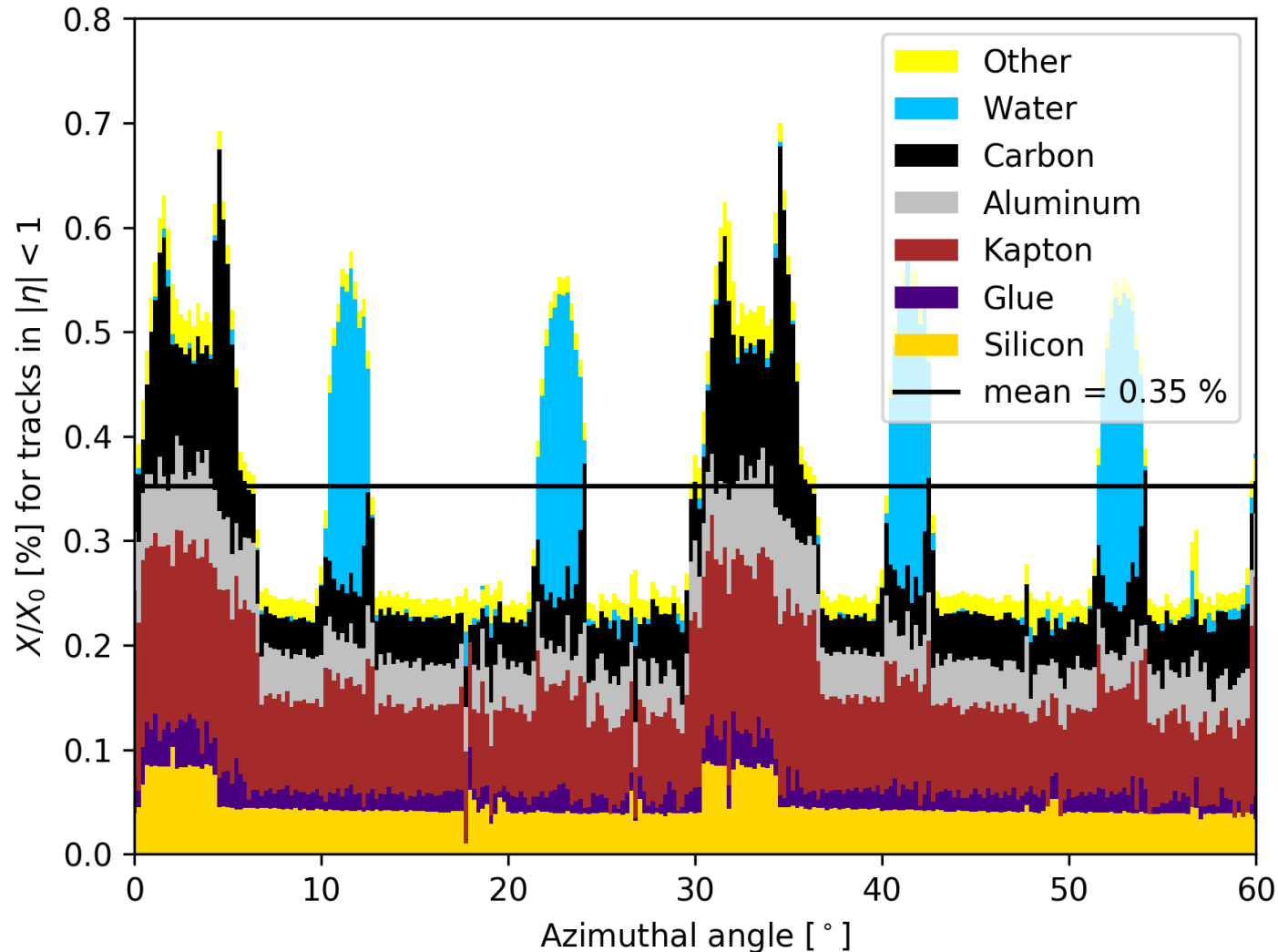
Layer 2 (20 staves)



- Already very good performance estimates for ITS2
- Still, further improvements for the measurements of heavy-flavour hadrons and low-mass di-leptons possible
- **Key questions:**
 - 👉 Can we get even lighter?
 - 👉 Can we get even closer?



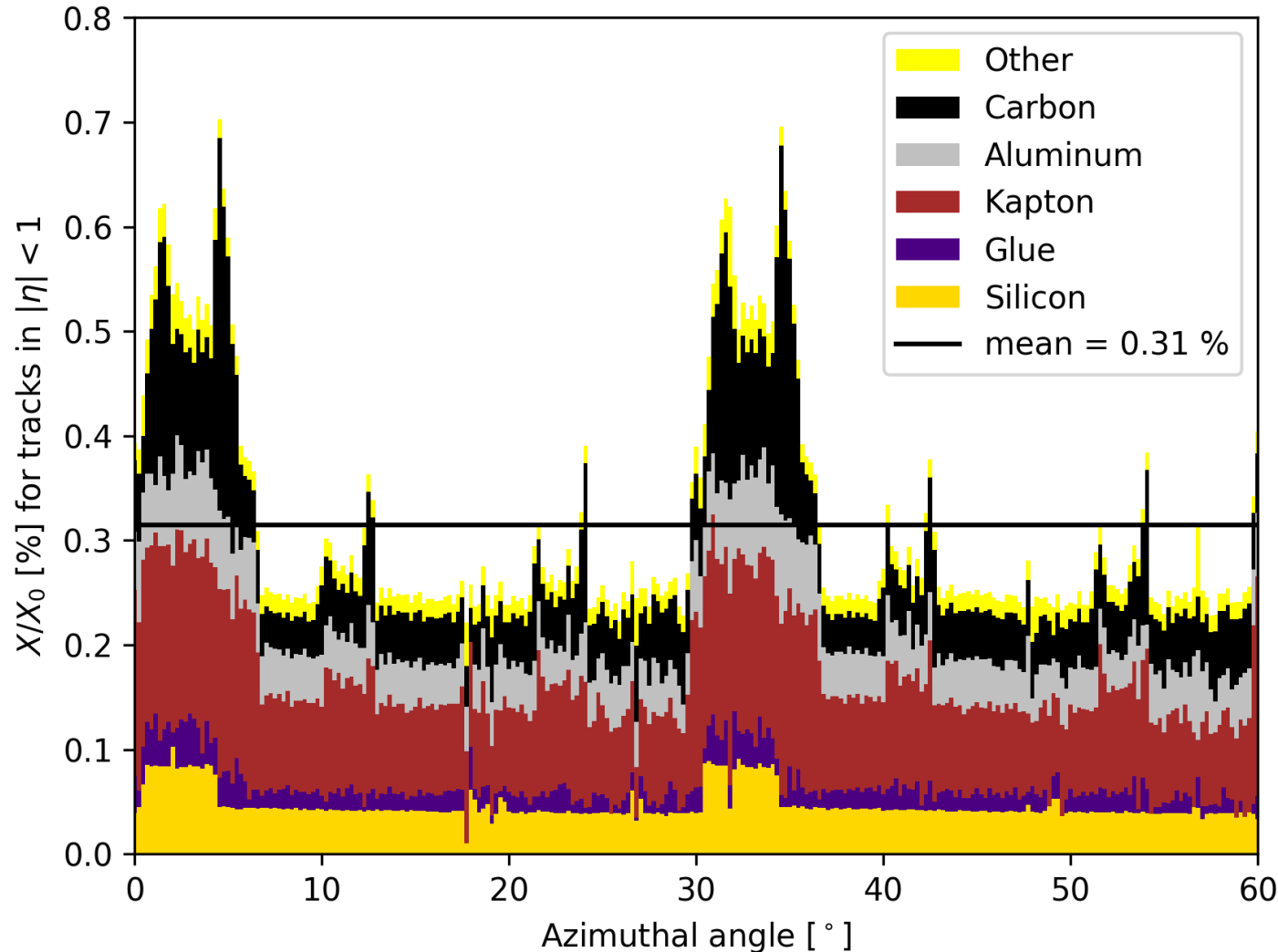
- Si only 1/7th of total material
- Irregularities due to overlaps + support/cooling



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Remove cooling

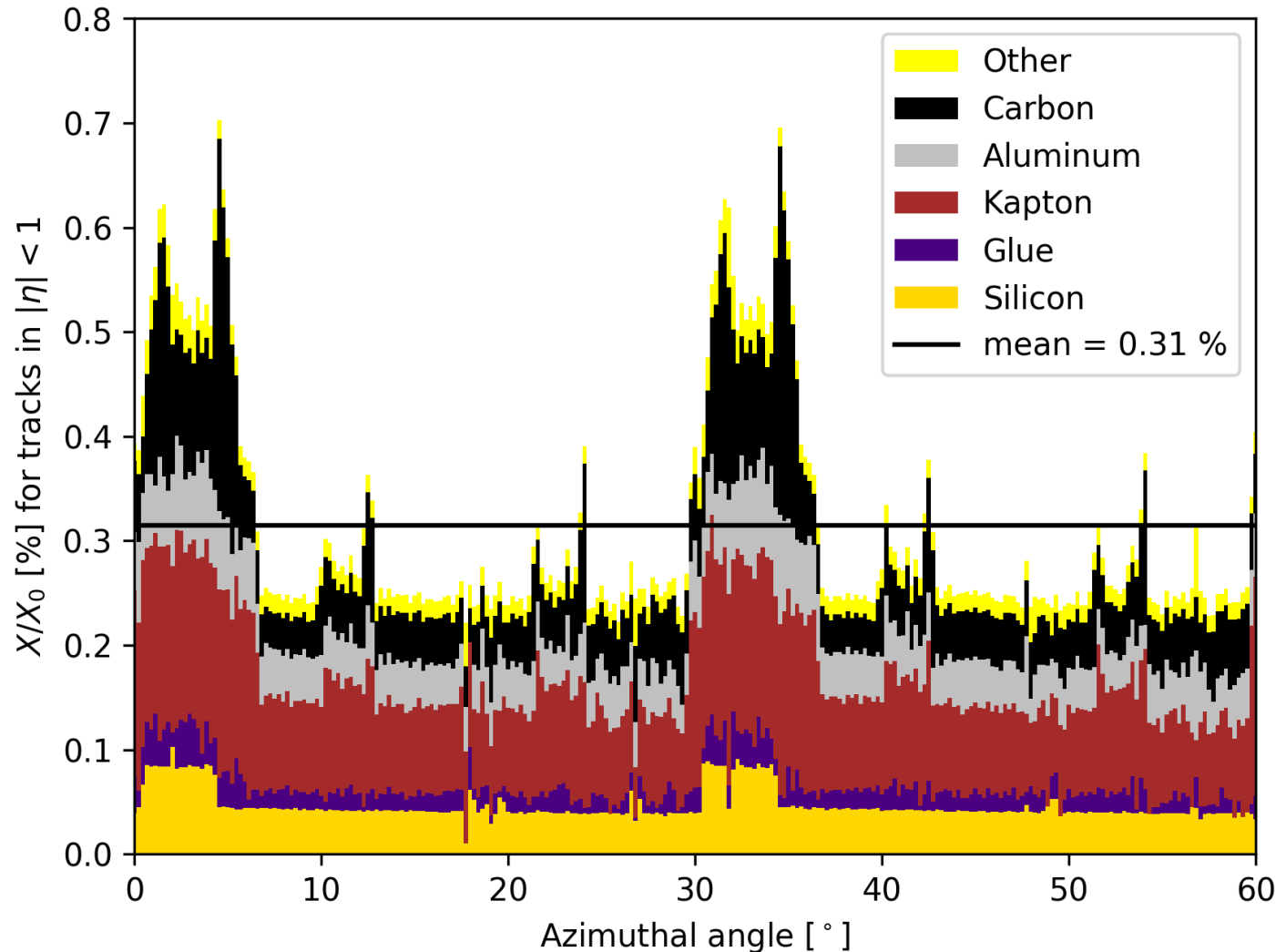
👉 reduce power consumption in fiducial volume $< 20 \text{ mW/cm}^2$



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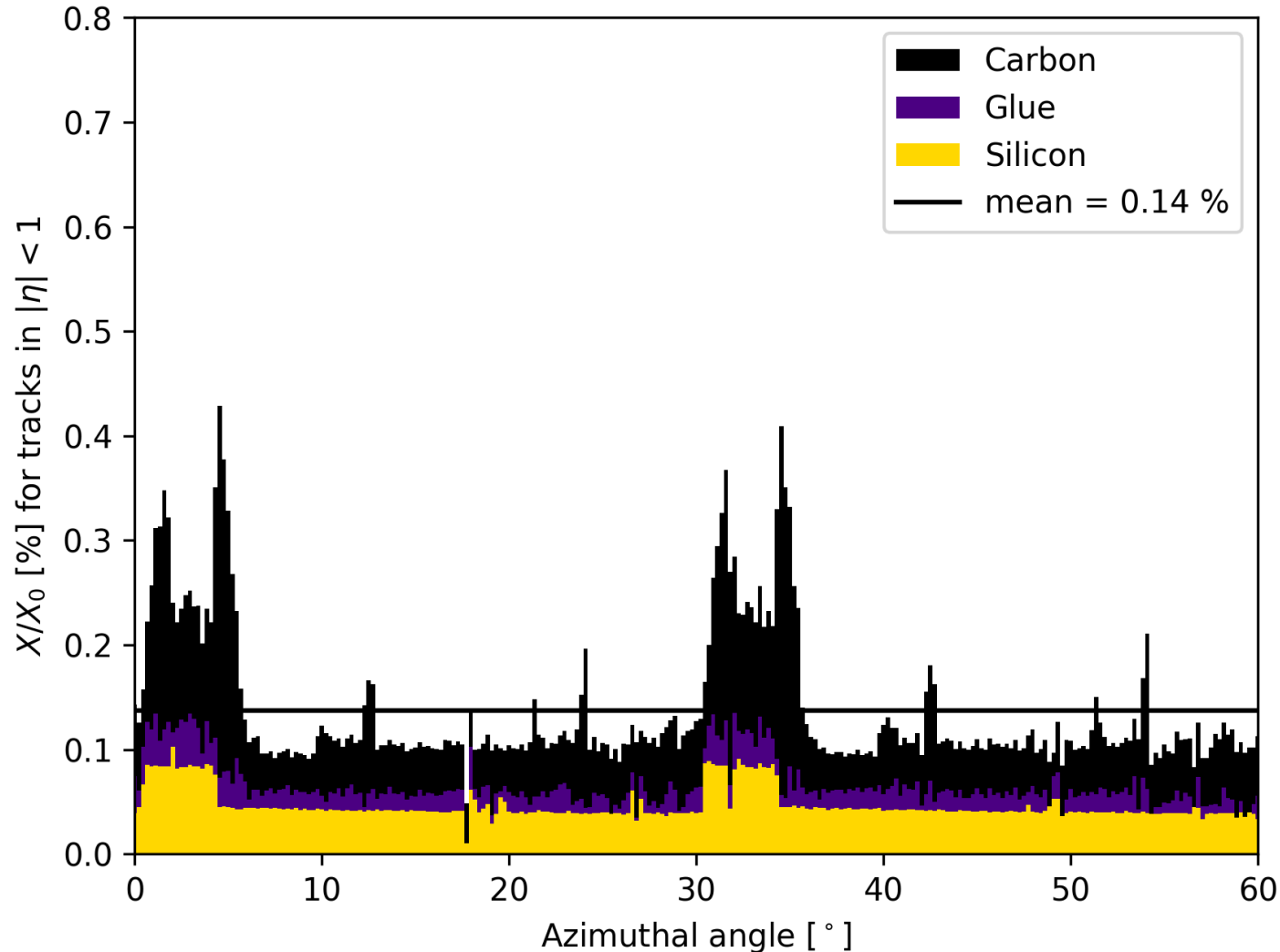
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Remove cooling

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Remove external data lines + power distribution

➡ make a single large chips and use CMOS metal layers



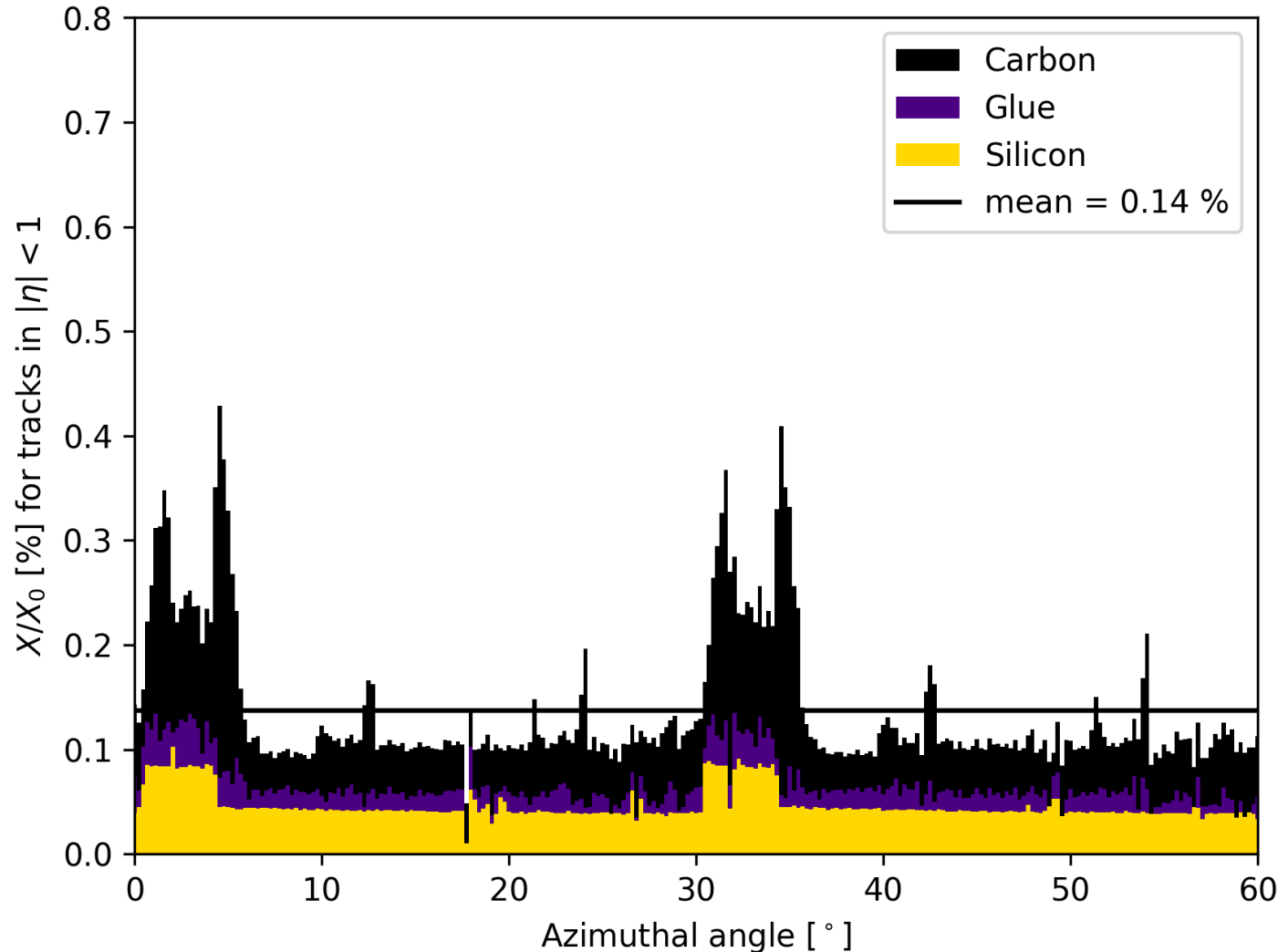
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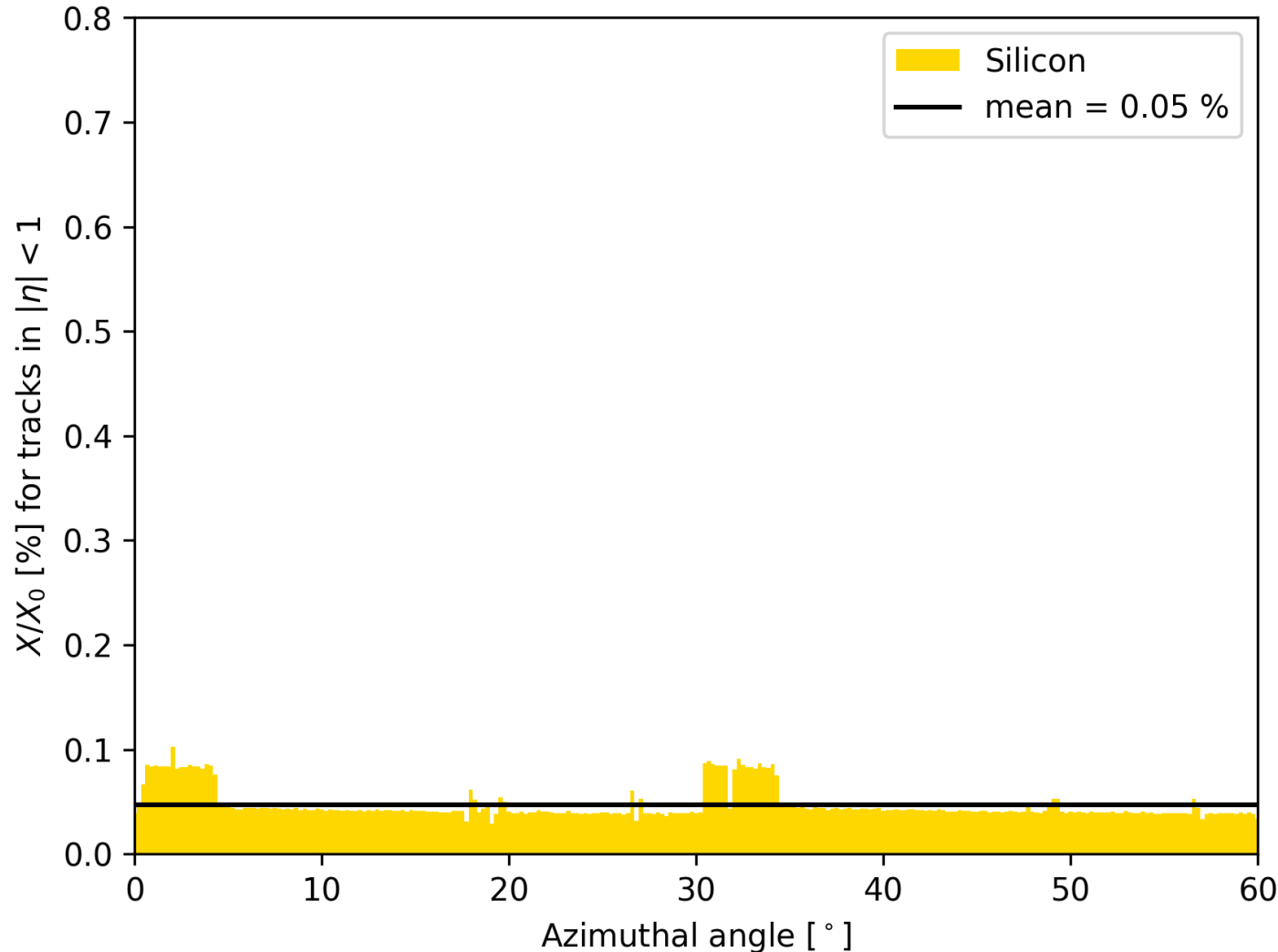
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Remove external data lines + power distribution

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Move mechanical support outside acceptance

- ➡ benefit from increased stiffness by rolling Si wafers



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Remove cooling

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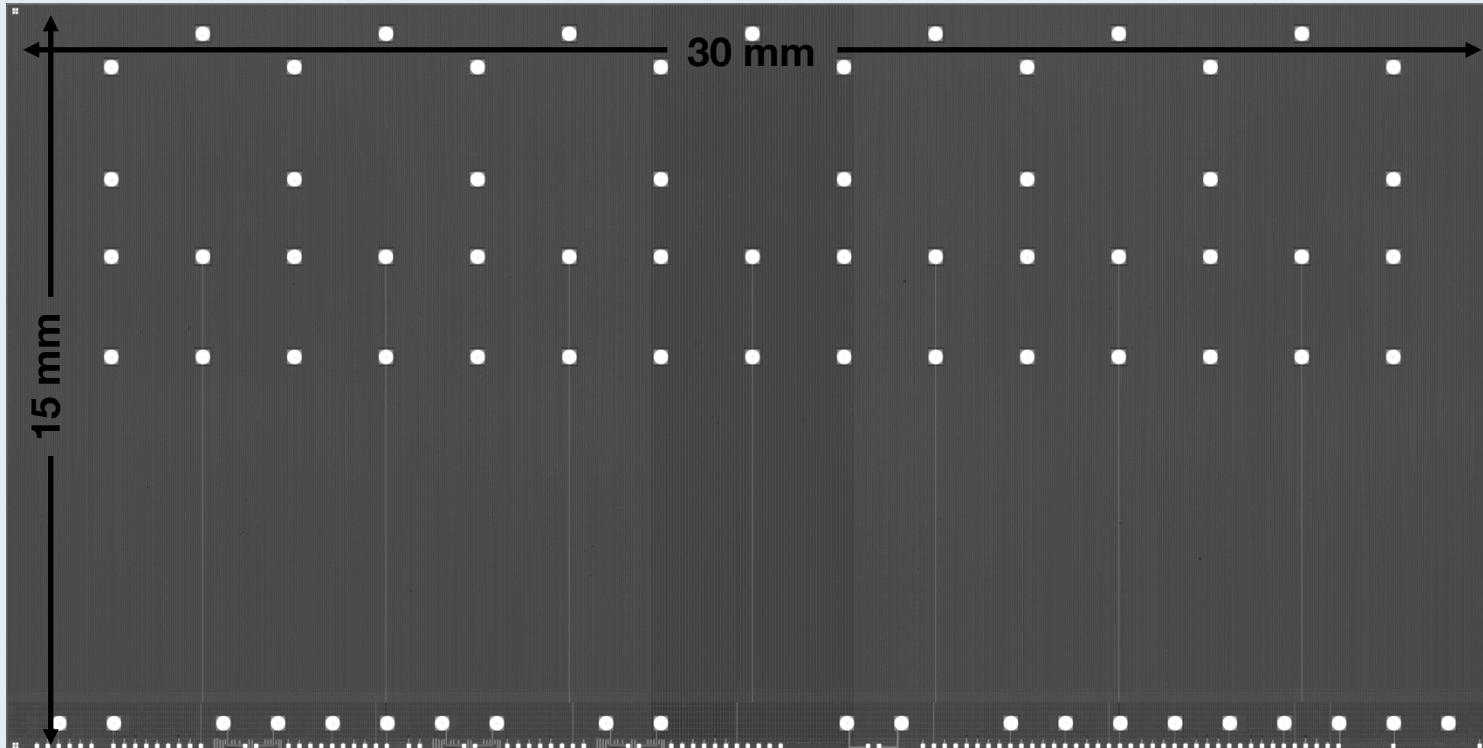
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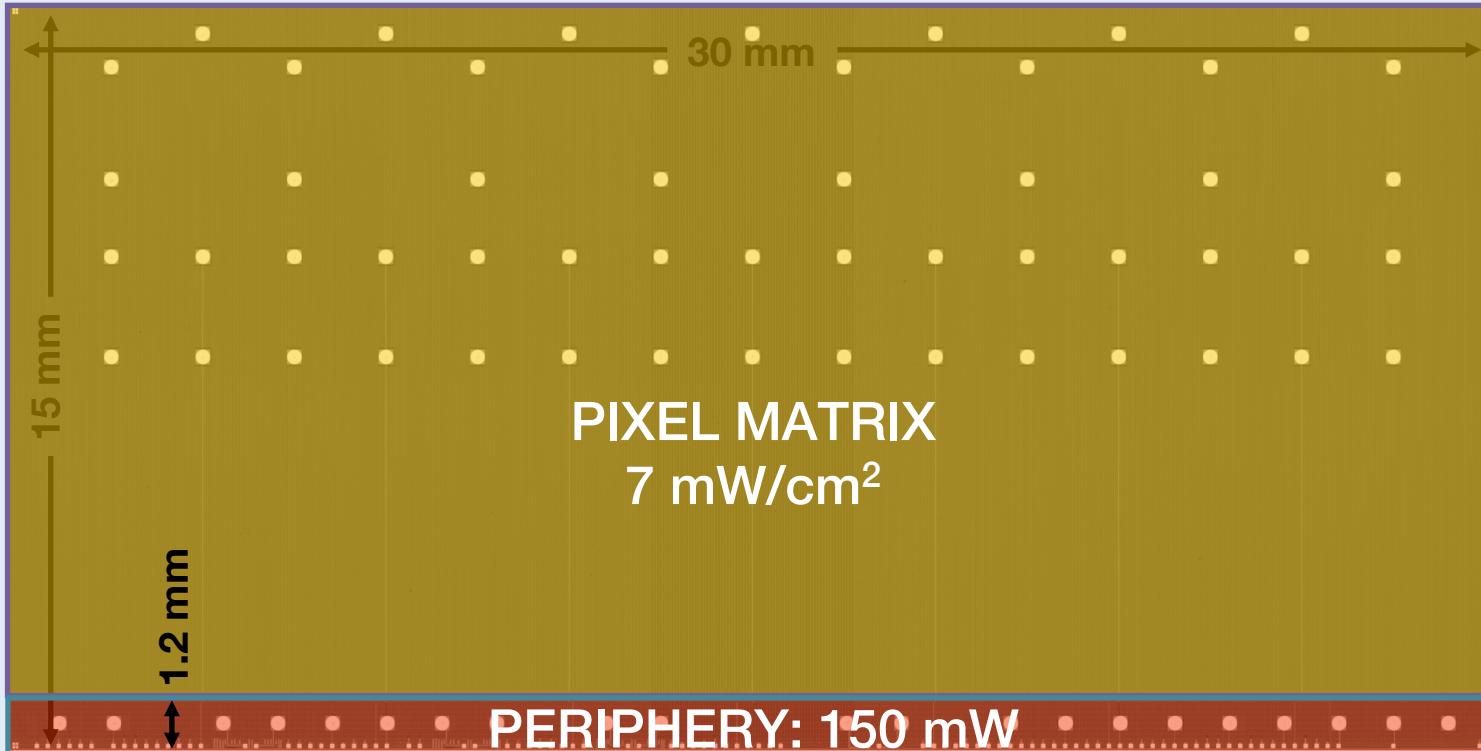
- ➡ benefit from increased stiffness by rolling Si wafers

ALPIDE



- Air cooling possible as of $\sim 20 \text{ mW/cm}^2$
 - 👉 ALPIDE already close: $\sim 40 \text{ mW/cm}^2$

ALPIDE

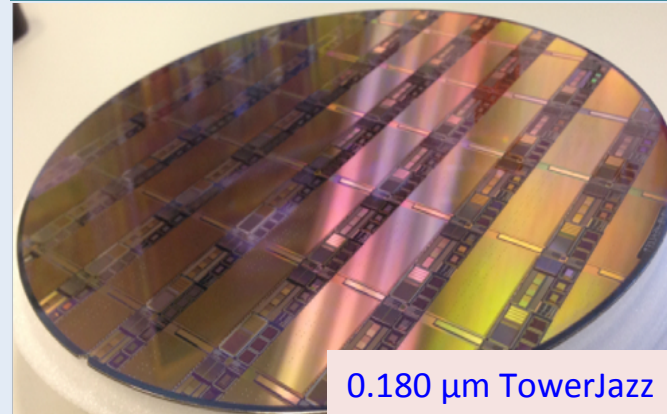


- Air cooling possible as of $\sim 20 \text{ mW/cm}^2$
 - ☞ ALPIDE already close: $\sim 40 \text{ mW/cm}^2$

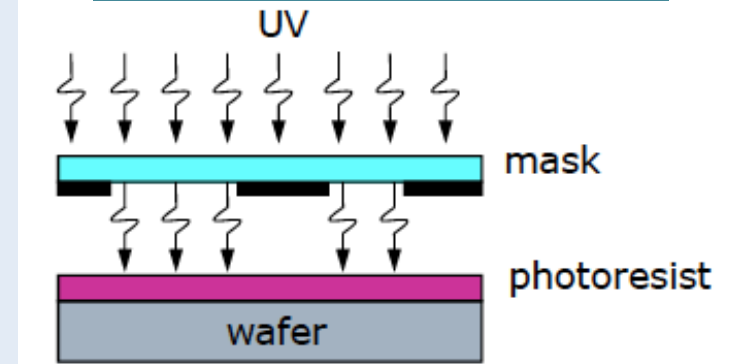
Actually largely sufficient if periphery outside fiducial volume

- Chip size is traditionally limited by CMOS manufacturing (“reticle size”)
- New option: **stitching**, i.e. aligned exposures of given parts of a reticle to produce a larger circuit
- Feasible, but needs specific design
- On a with **300 mm wafer** (available in 65 nm technology node), a single chip fits **a full half-layer**

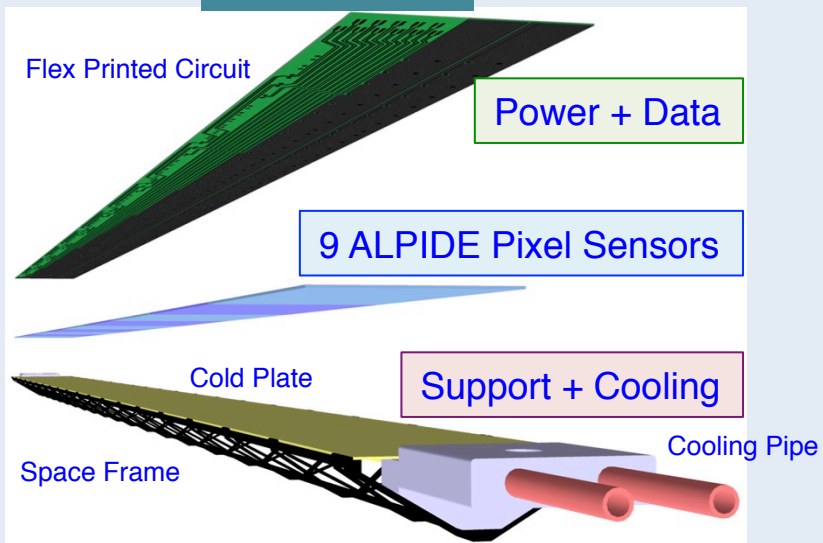
200 mm ALPIDE prototype wafer



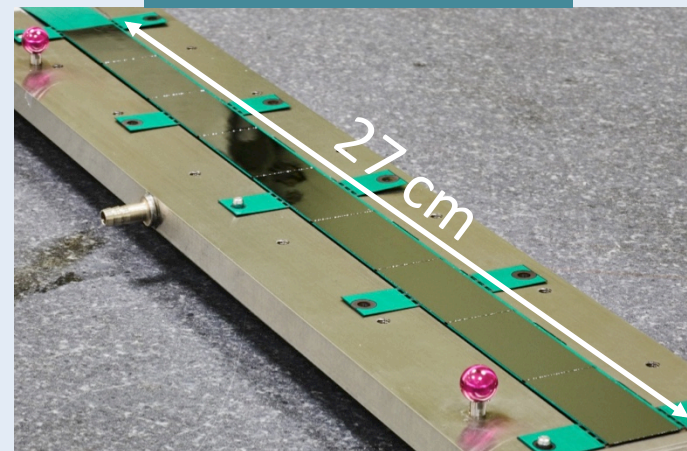
Principle of photolithography



Stave Design

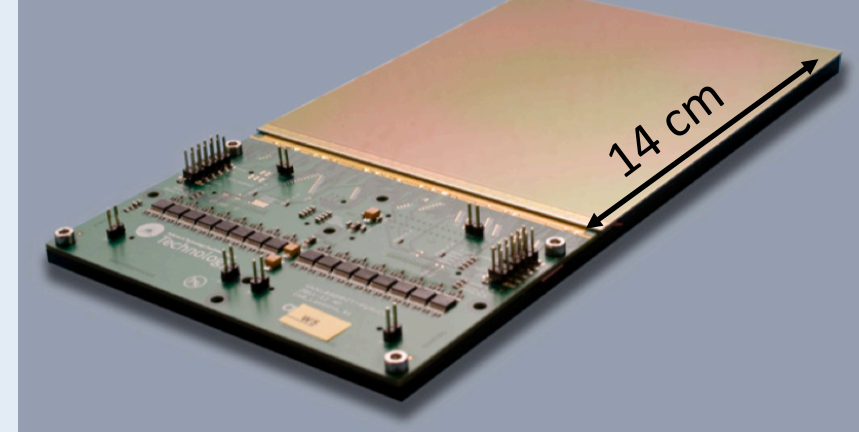


FPC + 9 ALPIDE chips



Wafer-scale sensor

Courtesy: R. Turchetta, Rutherford Appleton Laboratory



- Bending Si wafers + circuits is possible!

D.A. van den Ende et al., *Microelectronics Reliability*, vol. 54, pp 2860-2870, 2014
<http://dx.doi.org/10.1016/j.microrel.2014.07.125>

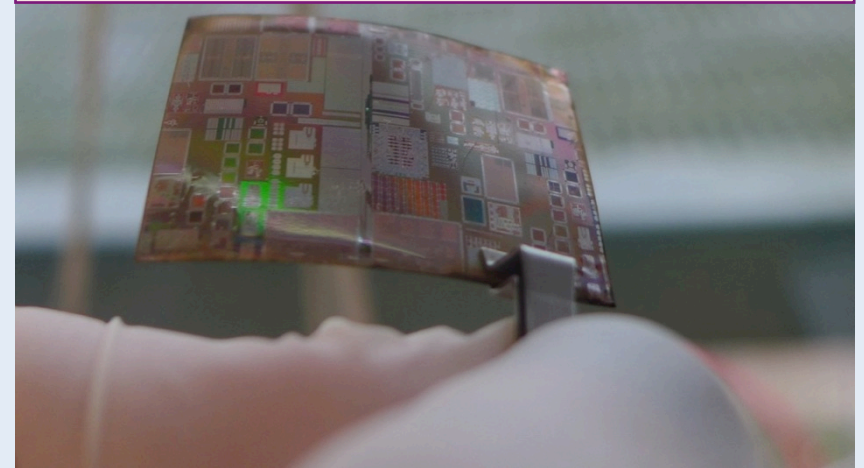
| Die type | Front/back side | Ground/polished/plasma | Bumps | Die thickness (μm) | CDS (MPa) | Weibull modulus | MDS (MPa) | r_{min} (mm) |
|----------|-----------------|------------------------|-------|---------------------------------|-----------|-----------------|-----------|-----------------------|
| Blank | Front | Ground | No | 15–20 | 1263 | 7.42 | 691 | 2.46 |
| Blank | Back | Ground | No | 15–20 | 575 | 5.48 | 221 | 7.72 |
| IZM28 | Front | Ground | Yes | 15–20 | 1032 | 9.44 | 636 | 2.70 |
| IZM28 | Back | Ground | Yes | 15–20 | 494 | 2.04 | 52 | 32.7 |
| Blank | Back | Polished | No | 25–35 | 1044 | 4.17 | 334 | 7.72 |
| IZM28 | Back | Polished | Yes | 25–35 | 482 | 2.98 | 107 | 24.3 |
| Blank | Back | Plasma | Yes | 18–22 | 2340 | 12.6 | 679 | 2.50 |
| IZM28 | Front | Plasma | Yes | 18–22 | 1207 | 2.64 | 833 | 2.05 |
| IZM28 | Back | Plasma | Yes | 18–22 | 2139 | 3.74 | 362 | 4.72 |

- Radii much smaller than our needs are obtained
- Circuit-specific R&D is needed
- R&D contacts with industrial partners have started
- Investigating options to start with existing ALPIDE chips + wafers

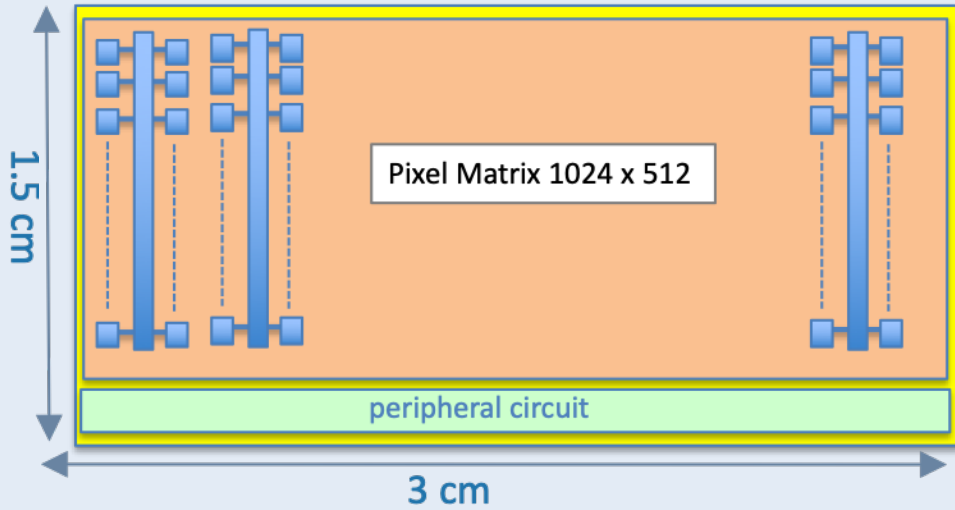
Silicon Genesis: 20 micron thick wafer



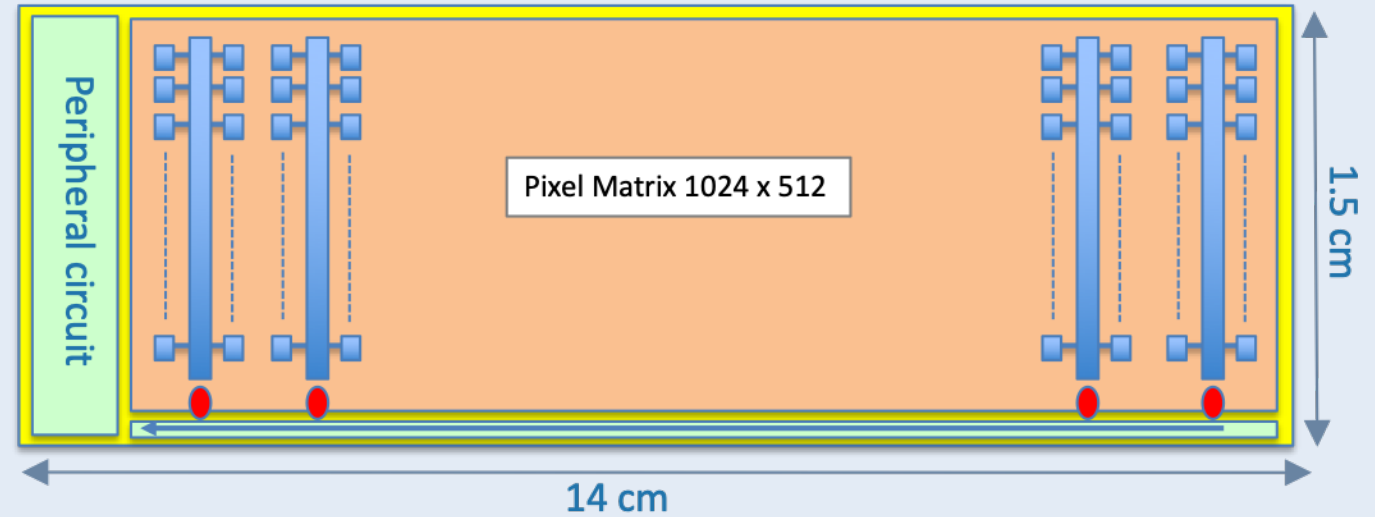
Chipworks: 30 μm -thick RF-SOI CMOS



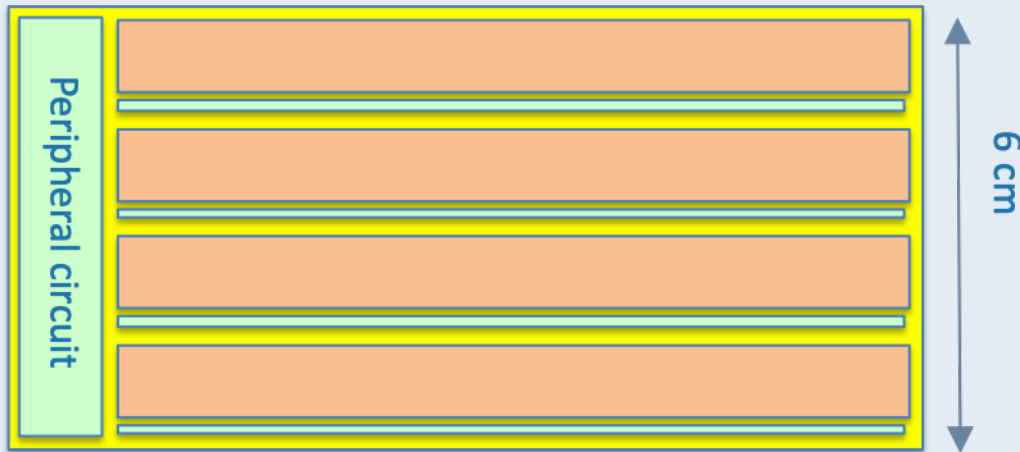
ALPIDE Chip



1D stitched sensor (z direction)



2D stitched sensor – wafer-scale



By instantiating multiple times the same circuits in the second dimension (ϕ) one can realize the sensors for the different layers. For example

- L0 = 14 cm x 6.0 cm
- L1 = 14 cm x 7.5 cm
- L2 = 14 cm x 9.0 cm

👉 achievable with wafers available in 180 nm technology node (ALPIDE technology)

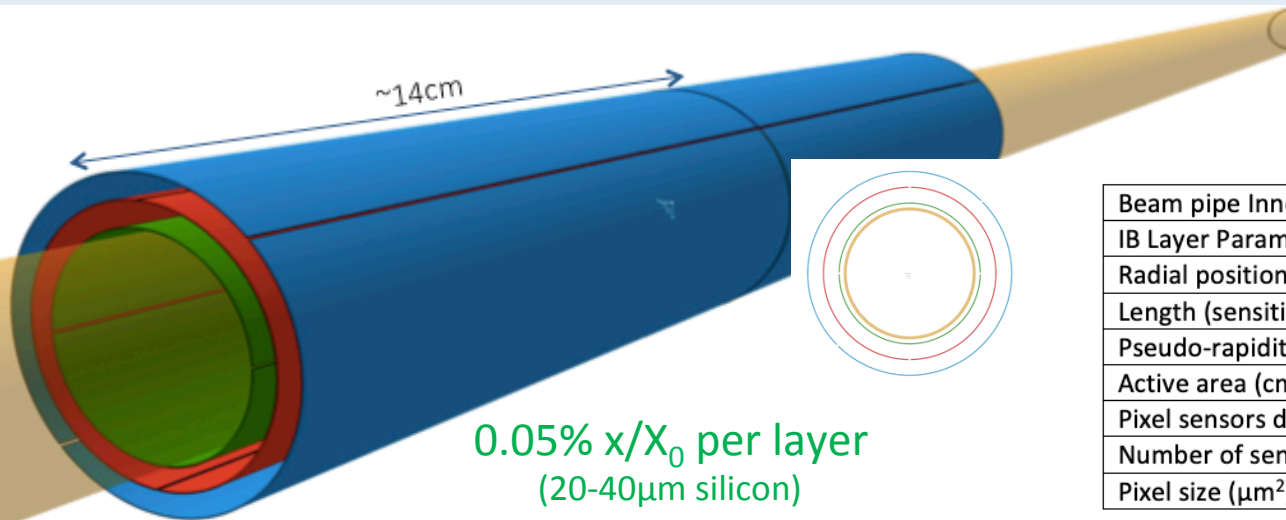
EoI for new ultra-light Inner Barrel in LS3 (CDS, ALICE-PUBLIC-2018-013)

Recent silicon technologies (ultra-thin wafer-scale sensors) allow

- Eliminate active cooling \Rightarrow possible for power $< 20\text{mW}/\text{cm}^2$
- Eliminate electrical substrate \Rightarrow Possible if sensor covers the full stave length
- Sensors arranged with a perfectly cylindrical shape \Rightarrow sensors thinned to $\sim 30\mu\text{m}$ can be curved to a radius of 10-20mm

Truly cylindrical vertex detector

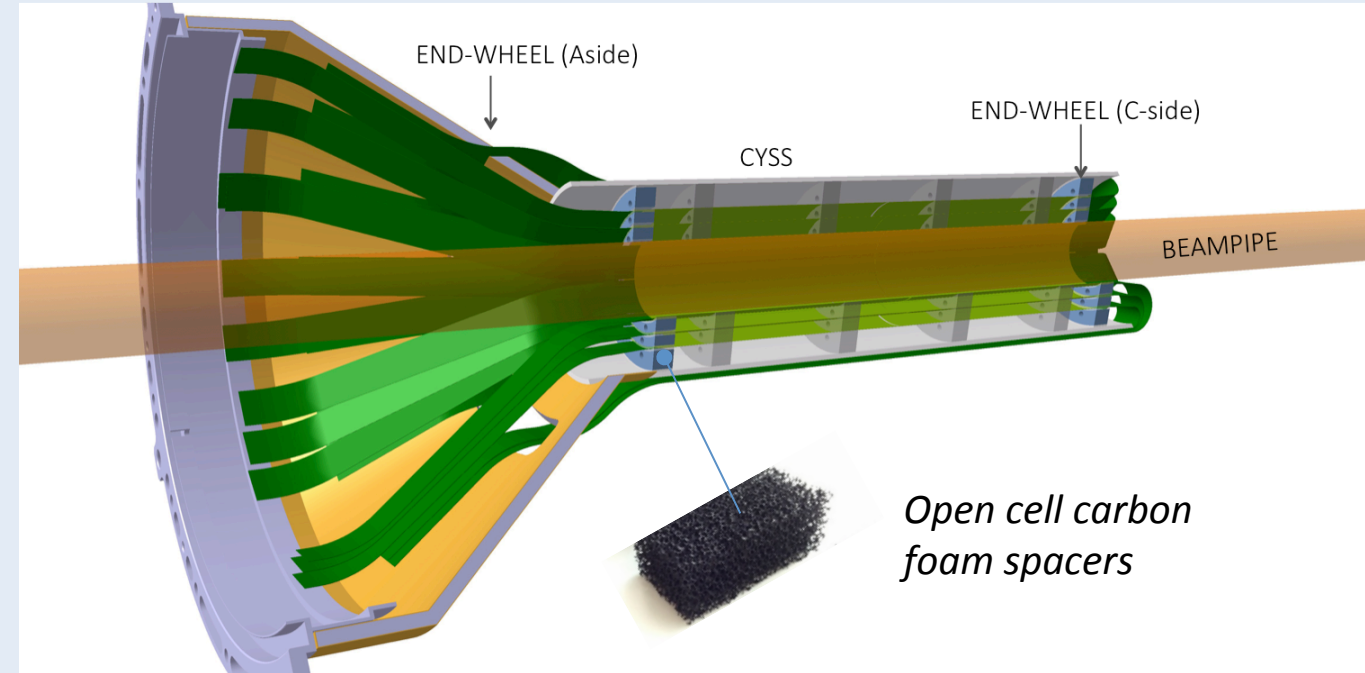
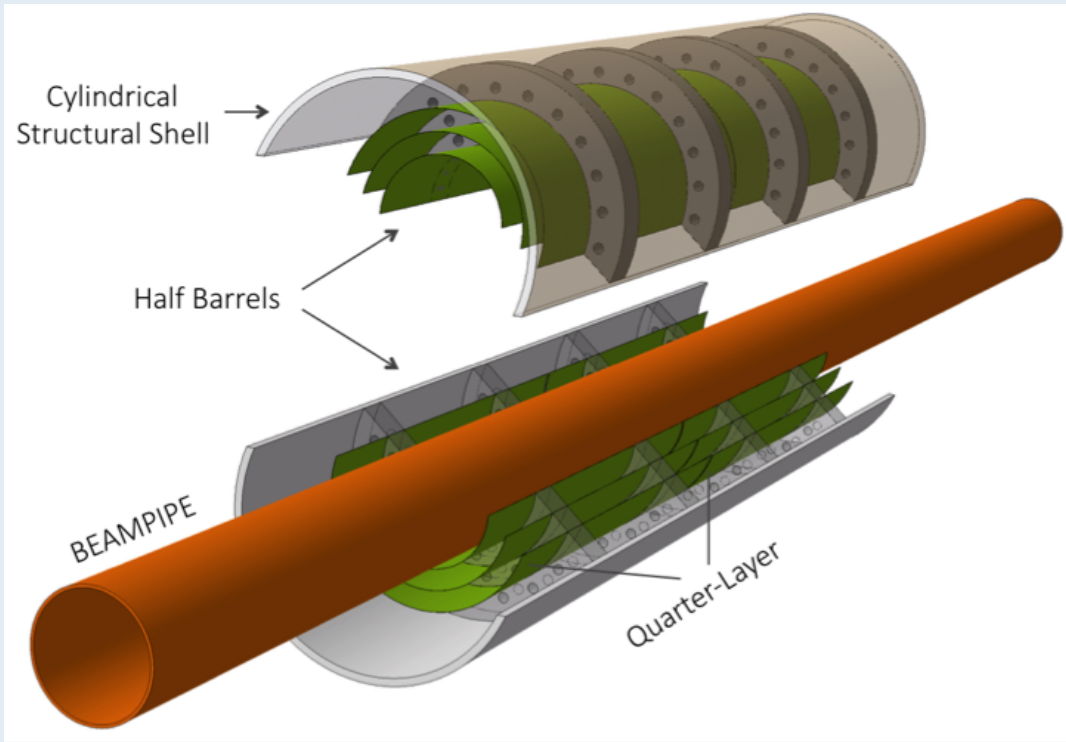
New Beampipe
IR 16 mm
 ΔR 0.5mm



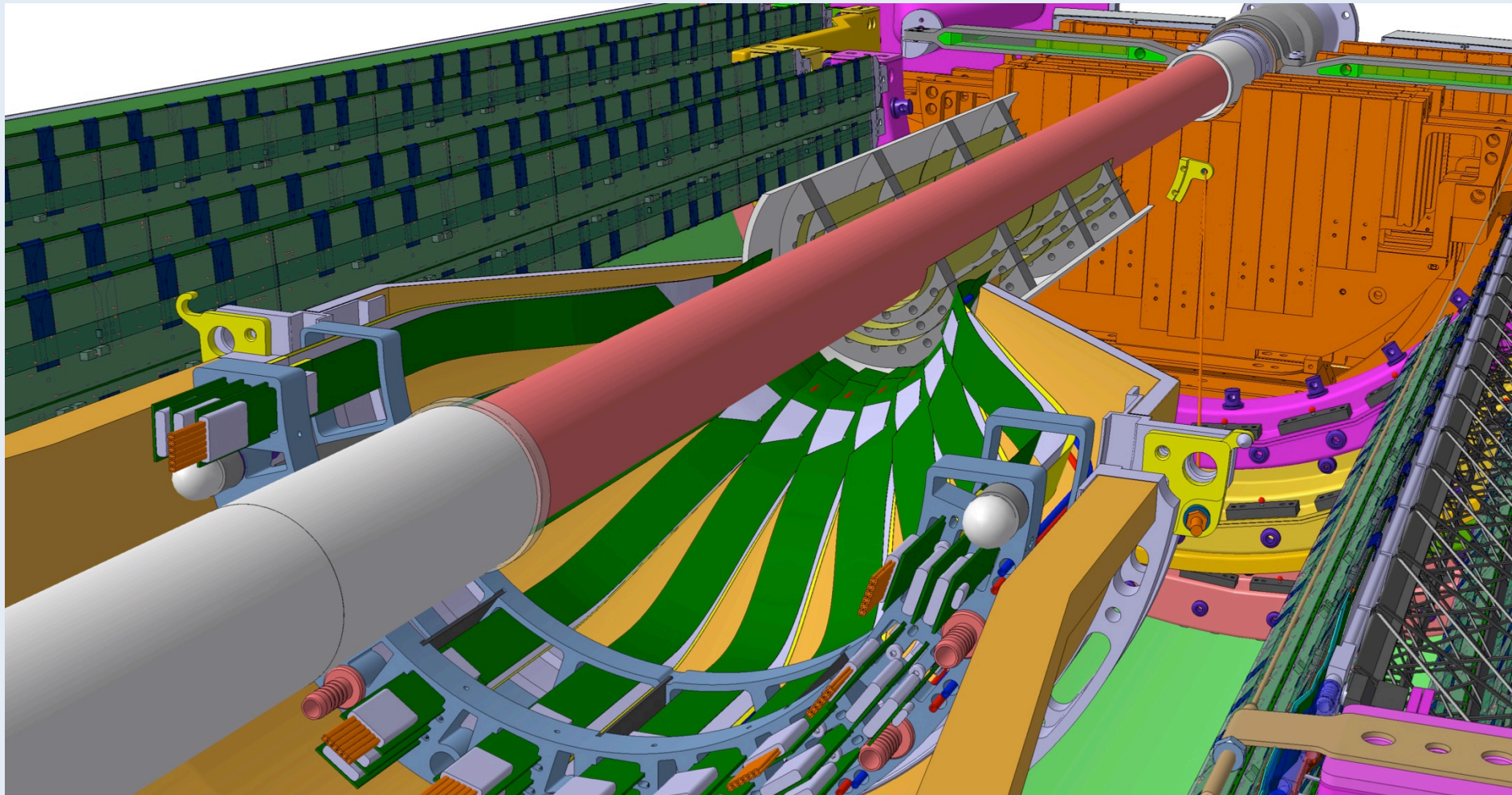
Pipe: $r \approx 16\text{mm}$, $\Delta R = 0.5\text{mm}$

L0: $r \approx 18\text{mm}$, L1: $r \approx 24\text{mm}$. L2: $r \approx 30\text{mm}$

| Beam pipe Inner/Outer Radius (mm) | 16.0/16.5 | | |
|---|-------------|------------|-----------|
| IB Layer Parameters | Layer 0 | Layer 1 | Layer 2 |
| Radial position (mm) | 18.0 | 24.0 | 30.0 |
| Length (sensitive area) (mm) | 300 | | |
| Pseudo-rapidity coverage | ± 2.5 | ± 2.3 | ± 2.0 |
| Active area (cm ²) | 610 | 816 | 1016 |
| Pixel sensors dimensions (mm ²) | 280 x 56.5 | 280 x 75.5 | 280 x 94 |
| Number of sensors per layer | 2 | | |
| Pixel size (μm^2) | O (10 x 10) | | |

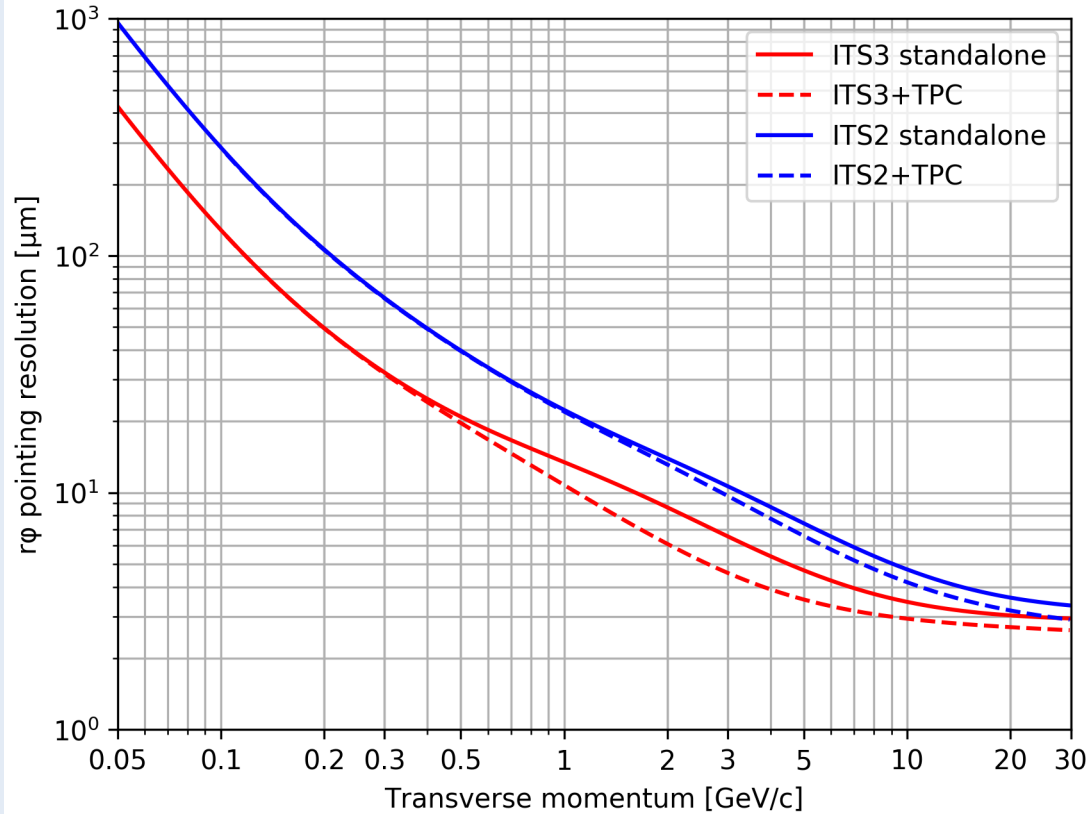


- Possible layout based on **air-cooling**
additional cooling at the extremities (**chip peripheries**)
- Sensors hold in place with **low-density carbon foam**
- Fixation into the experiment by surrounding support structure, as well as at both ends



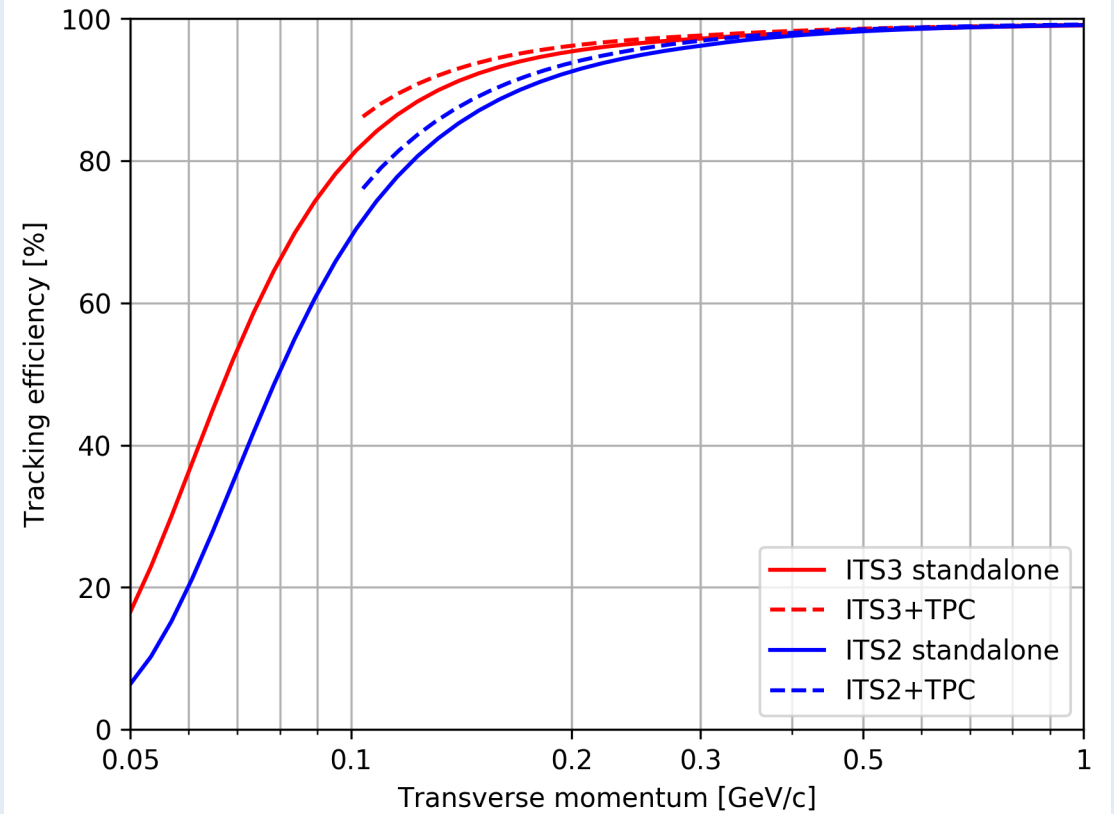
- 👉 Simply replace the Inner Barrel of ITS2
- 👉 Outer Barrel of ITS2 stays in place as is

Pointing resolution



Improvement of factor 2 over all momenta

Tracking efficiency



Large improvement for low transverse momenta

R&D 2020-2023

Wafer thinning + bending

2019 → Contact to industry

2019-2020 → First prototypes with ALPIDE chips and wafers

2021 on → Continue with specific prototypes

Stitched sensor development

2019-2020 → Technology test structures

2020-2022 → Prototyping chips

2022-2023 → Full-scale prototype + final chip

Technical Design Report 2022

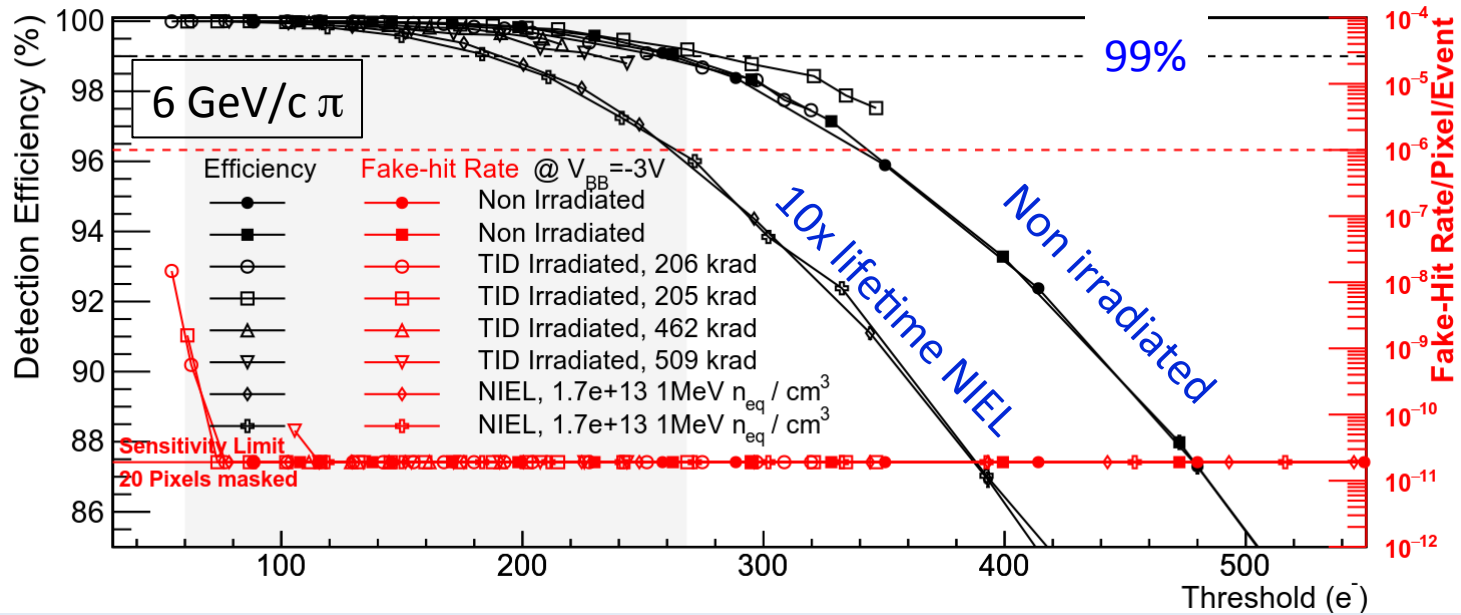
Construction 2024-2025

Installation during LS3

- With the ITS2 upgrade and ALPIDE, ALICE redefined the new state-of-the art in CMOS MAPS technology and its applications in HEP
- The used technology offers further opportunities, stitching, smaller feature size, bending that directly impact the key measurements that highly rely on precise vertexing and low material budget
- A detector conceived for studies of pp, pA and AA collisions at luminosities 50 times higher than possible with the LS2 upgraded ALICE detector
 - Enables rich physics program: from measurements with electromagnetic probes at ultra-low transverse momenta to precision physics in the charm and beauty sector
 - Tracking and vertexing capabilities over a wide momentum range down to a few tens of MeV/c
 - Particle ID via time-of-flight determination with about 20ps resolution. Electron and photon ID identification will be performed in a separate pixel shower detector
 - Unprecedented low material budget for the inner layers of 0.05% X_0 , with the innermost layers possibly positioned inside the beam pipe
- ALICE LS3 upgrade: three truly cylindrical inner barrel based on curved wafer-scale ultra-thin CMOS Active Pixel sensors

Thank You





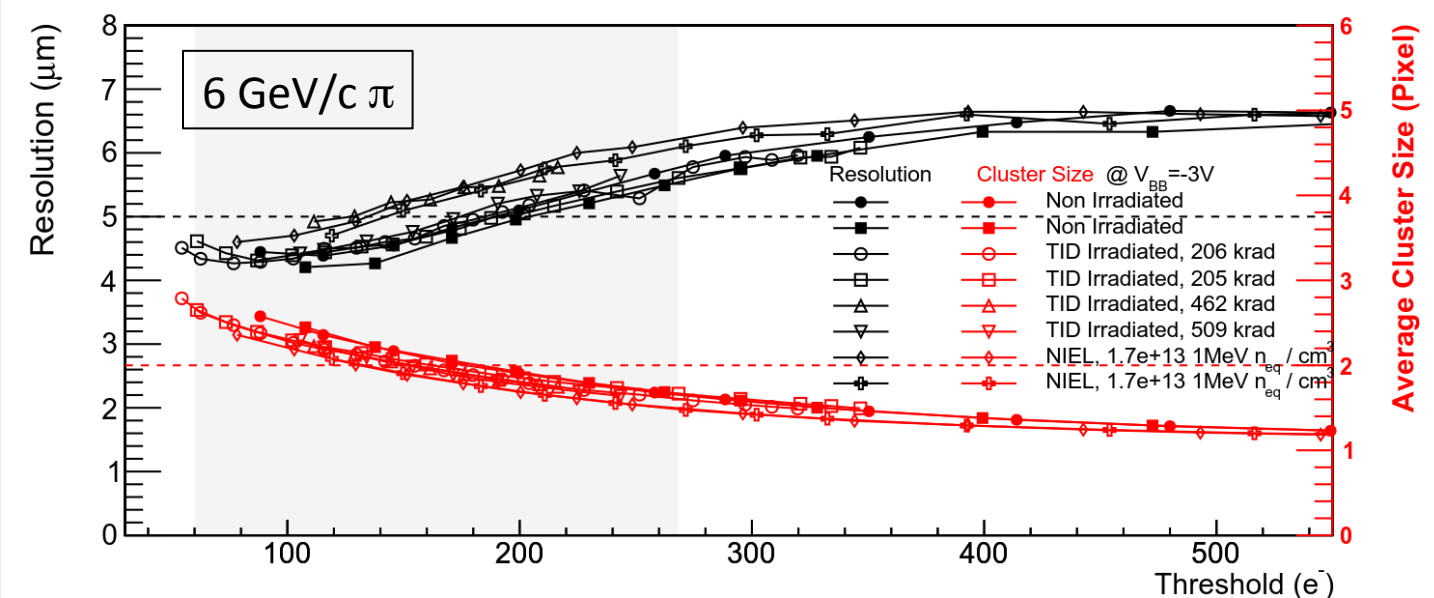
Large operational margin with only 10 masked pixels (0.002%), fake-hit rate $< 2 \times 10^{-11}$ pixel/event

Non irradiated and TID/NIEL chips similar performance

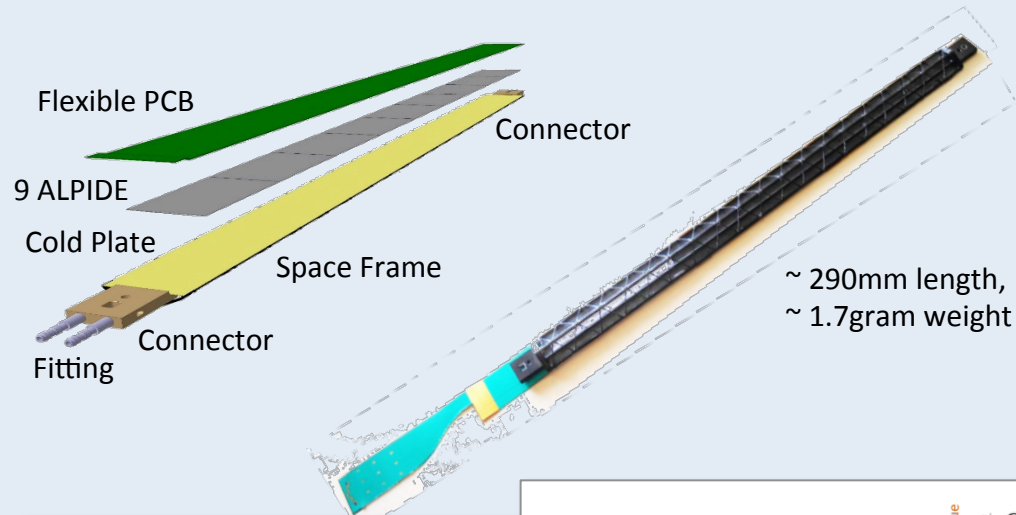
Nucl. Phys. A 967 (2017) 900-903

Nucl. Phys. A 967 (2017) 900-903

5 μm resolution @200 e^- threshold
Chip-to-chip negligible fluctuations



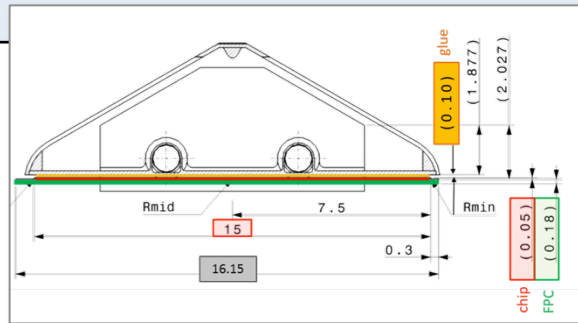
Inner Barrel Stave



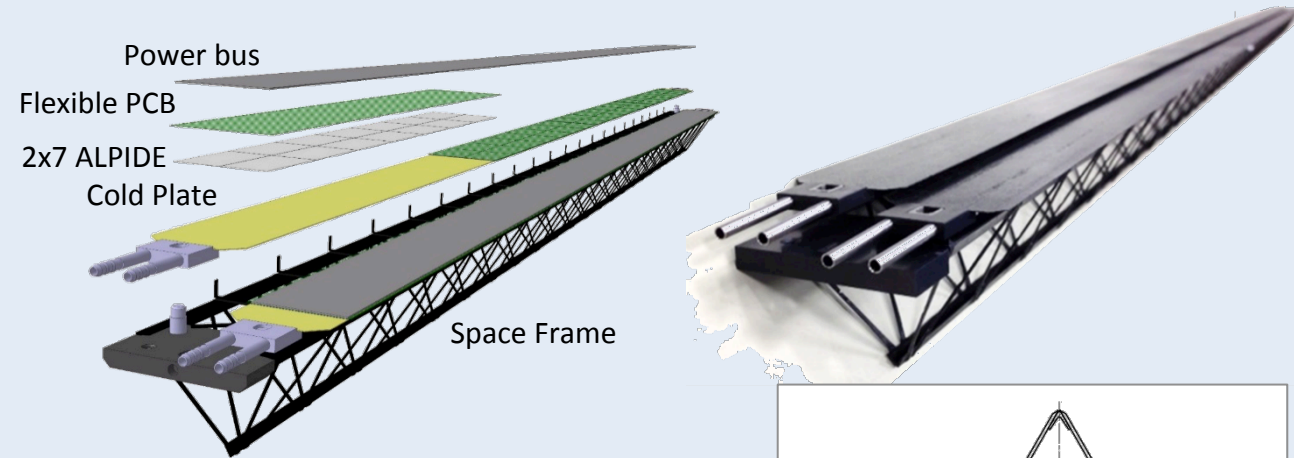
Radius (mm) 23, 31, 39
 Nr. Staves: 12, 16, 20
 Nr. Chips/ layer: 108, 144, 180

Length in z (mm): 271.2 mm
 Nr. chips/ Stave: 9
 Material thickness: ~0,3% X₀

Coolant Single-phase H₂O leak-less
 Pixel operational temperature < 30°C
 Pixel max temperature non-uniformity < 5°C
 Chip Power dissipation < 50mW/cm²



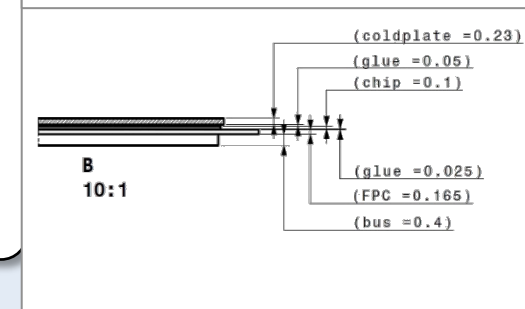
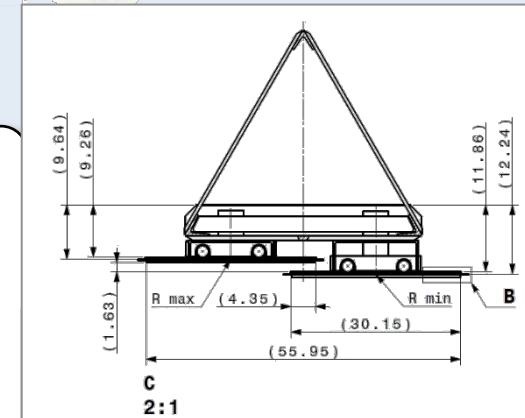
Outer Barrel Stave



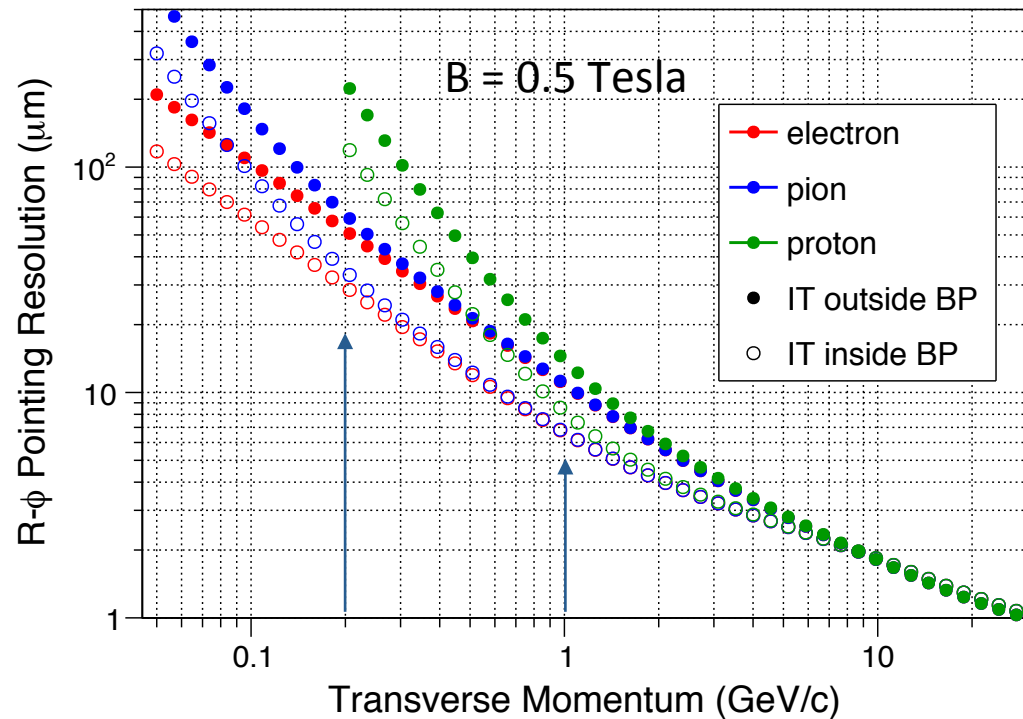
Radius (mm) 196, 245.4, 343.8, 393.3
 Nr. Staves: 24, 30, 42, 48
 Nr. Chips/ module: 2x7

Length in z (mm): 844.2 (ML), 1477.5 mm (OL)
 Nr. module/ Stave: 4 (ML), 7 (OL)
 Material thickness: ~1% X₀

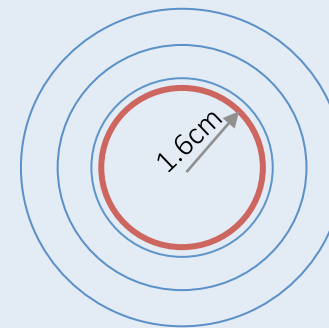
Coolant Single-phase H₂O leak-less
 Pixel operational temperature < 30°C
 Pixel max temperature non-uniformity < 5°C
 Chip Power dissipation < 40mW/cm²



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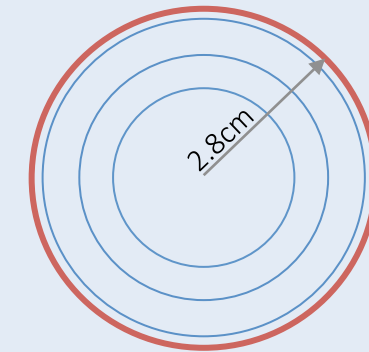


IT outside BP



IT (L_0, L_1, L_2)

IT inside BP



beam pipe (BP)

Pointing resolution (pions): $\approx 10 \mu\text{m}$ @ 1 GeV/c, $< 50 \mu\text{m}$ @ 200 MeV/c

It does not depend on B field

